No External Programming Voltage Needed

MSP430FG42x0 Family Members Include:

MSP430FG4250: 16KB+256B Flash Memory

256B RAM

MSP430FG4260: 24KB+256B Flash Memory

256B RAM

MSP430FG4270: 32KB+256B Flash Memory

256B RAM

For Complete Module Descriptions, See

For Additional Device Information. See

MSP430FG42x0 Device Erratasheet,

MSP430x4xx Family User's Guide,

Literature Number SLAU056

Integrated LCD Driver With Contrast

Programmable Code Protection by Security

Serial Onboard Programming,

Control for up to 56 Segments

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- Low Supply-Voltage Range, 1.8 V to 3.6 V
- **Ultralow-Power Consumption:** Active Mode: 250 µA at 1 MHz, 2.2 V Standby Mode: 1.1 µA Off Mode (RAM Retention): 0.1 µA
- **Five Power Saving Modes**
- Wake-Up From Standby Mode in Less Than 6 us
- **16-Bit RISC Architecture, 125-ns Instruction Cycle Time**
- 16-Bit Sigma-Delta A/D Converter With • **Internal Reference and Five Differential** Analog Inputs
- 12-Bit D/A Converter
- **Two Configurable Operational Amplifiers**
- 16-Bit Timer A With Three • **Capture/Compare Registers**
- **Brownout Detector**
- **Bootstrap Loader**

description

Literature Number SLAZ038 The Texas Instruments MSP430 family of ultralow-power microcontrollers consist of several devices featuring

different sets of peripherals targeted for various applications. The architecture, combined with five low-power modes, is optimized to achieve extended battery life in portable measurement applications. The device features a powerful 16-bit RISC CPU, 16-bit registers, and constant generators that contribute to maximum code efficiency. The digitally controlled oscillator (DCO) allows wake-up from low-power modes to active mode in less than 6 µs.

•

Fuse

The MSP430FG42x0 is a microcontroller configuration with a 16-bit timer, a high-performance 16-bit sigma-delta A/D converter, 12-bit D/A converter, two configurable operational amplifiers, 32 I/O pins, and a liquid crystal display driver.

Typical applications for this device include analog and digital sensor systems, digital motor control, remote controls, thermostats, digital timers, hand-held meters, etc.

	PACKAGED DEVICES			
T _A	PLASTIC 48-PIN SSOP (DL)	PLASTIC 48-PIN QFN (RGZ)		
	MSP430FG4250IDL	MSP430FG4250IRGZ		
–40°C to 85°C	MSP430FG4260IDL	MSP430FG4260IRGZ		
	MSP430FG4270IDL	MSP430FG4270IRGZ		

AVAILABLE OPTIONS



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications. These devices have limited built-in ESD protection.



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pin designation, DL package

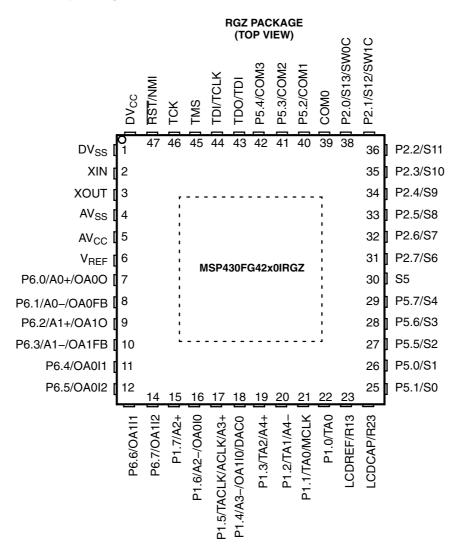
		(TOP VIEW)		
r				1
ΤΟΟ/ΤΟΙ [10		48	P5.4/COM3
TDI/TCLK	2		47	P5.3/COM2
TMS	3		46	P5.2/COM1
тск 🗖	4		45	
RST/NMI	5		44	P2.0/S13/SW0C
DV _{CC}	6		43	P2.1/S12/SW1C
DV _{SS}	7		42	P2.2/S11
XIN 🗖	8		41	P2.3/S10
ΧΟυΤ [9	MSP430FG42x0IDL	40	P2.4/S9
AV _{SS}	10		39	P2.5/S8
AV _{CC}	11		38	P 2.6/S7
V _{REF}	12		37	P2.7/S6
P6.0/A0+/OA0O	13		36] S5
P6.1/A0–/OA0FB [14		35	P 5.7/S4
P6.2/A1+/OA1O [15		34	P 5.6/S3
P6.3/A1–/OA1FB [16		33	P 5.5/S2
P6.4/OA0I1	17		32	P 5.0/S1
P6.5/OA0I2	18		31	P5.1/S0
P6.6/OA1I1	19		30	LCDCAP/R23
P6.7/OA1I2	20		29	LCDREF/R13
P1.7/A2+	21		28	P1.0/TA0
P1.6/A2–/OA0I0	22		27	P1.1/TA0/MCLK
P1.5/TACLK/ACLK/A3+	23		26	P1.2/TA1/A4-
P1.4/A3-/OA1I0/DAC0	24		25	P1.3/TA2/A4+

DL PACKAGE



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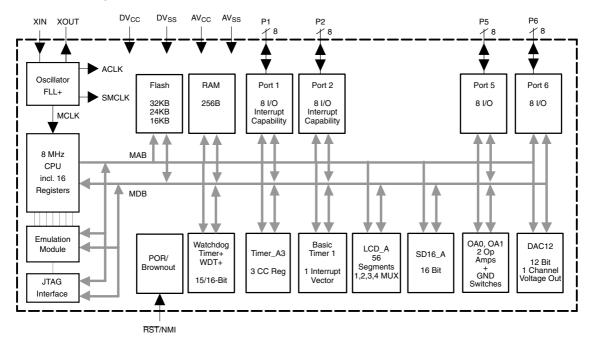
pin designation, RGZ package





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functional block diagram



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Terminal Functions

TERMINAL					
NAME	DL NO.	RGZ NO.	I/O	DESCRIPTION	
TDO/TDI	1	43	I/O	Test data output. TDO/TDI data output or programming data input terminal	
TDI/TCLK	2	44	I	Test data input / test clock input. The device protection fuse is connected to TDI/TCLK.	
TMS	3	45	I	Test mode select. TMS is used as an input port for device programming and test.	
TCK	4	46	I	Test clock. TCK is the clock input port for device programming and test.	
RST/NMI	5	47	Ι	General-purpose digital I/O / reset input / nonmaskable interrupt input	
DV _{CC}	6	48		Digital supply voltage, positive terminal	
DV _{SS}	7	1		Digital supply voltage, negative terminal	
XIN	8	2	Ι	Input terminal of crystal oscillator XT1	
XOUT	9	3	0	Output terminal of crystal oscillator XT1	
AV _{SS}	10	4		Analog supply voltage, negative terminal	
AV _{CC}	11	5		Analog supply voltage, positive terminal	
V _{REF}	12	6	I/O	Analog reference voltage	
P6.0/A0+/OA0O	13	7	I/O	General-purpose digital I/O / analog input A0+ / OA0 output	
P6.1/A0-/OA0FB	14	8	I/O	General-purpose digital I/O / analog input A0- / OA0 feedback input	
P6.2/A1+/OA1O	15	9	I/O	General-purpose digital I/O / analog input A1+ / OA1 output	
P6.3/A1-/OA1FB	16	10	I/O	General-purpose digital I/O / analog input A1- / OA1 feedback input	
P6.4/OA0I1	17	11	I/O	General-purpose digital I/O / OA0 input multiplexer on -terminal	
P6.5/OA0I2	18	12	I/O	General-purpose digital I/O / OA0 input multiplexer on -terminal	
P6.6/OA1I1	19	13	I/O	General-purpose digital I/O / OA1 input multiplexer on -terminal	
P6.7/OA1I2	20	14	I/O	General-purpose digital I/O / OA1 input multiplexer on -terminal	
P1.7/A2+	21	15	I/O	General-purpose digital I/O / analog input A2+	
P1.6/A2-/OA0I0	22	16	I/O	General-purpose digital I/O / analog input A2– / OA0 input multiplexer on +terminal	
P1.5/TACLK/ACLK/A3+	23	17	I/O	General-purpose digital I/O / Timer_A, clock signal TACLK input / ACLK output (divided by 1, 2, 4, or 8) / analog input A3+	
P1.4/A3-/OA1I0/DAC0	24	18	I/O	General-purpose digital I/O / analog input A3– / OA1 input multiplexer on +terminal / DAC12 output	
P1.3/TA2/A4+	25	19	I/O	General-purpose digital I/O / Timer_A, Capture: CCI2A, compare: Out2 output / analog input A4+	
P1.2/TA1/A4-	26	20	I/O	General-purpose digital I/O / Timer_A, Capture: CCI1A, compare: Out1 output / analog input A4–	
P1.1/TA0/MCLK	27	21	I/O	General-purpose digital I/O / Timer_A. Capture: CCI0B / MCLK output. Note: TA0 is only an input on this pin / BSL Receive	
P1.0/TA0	28	22	I/O	General-purpose digital I/O / Timer_A. Capture: CCI0A input, compare: Out0 output / BSL transmit	
LCDREF/R13	29	23		External LCD reference voltage input / input port of third most positive analog LCD level (V4 or V3)	
LCDCAP/R23	30	24		Capacitor connection for LCD charge pump / input port of second most positive analog LCD level (V2)	
P5.1/S0	31	25	I/O	General-purpose digital I/O / LCD segment output 0	
P5.0/S1	32	26	I/O	General-purpose digital I/O / LCD segment output 1	
P5.5/S2	33	27	I/O	General-purpose digital I/O / LCD segment output 2	
P5.6/S3	34	28	I/O	General-purpose digital I/O / LCD segment output 3	
P5.7/S4	35	29	I/O	General-purpose digital I/O / LCD segment output 4	
S5	36	30	0	LCD segment output 5	
	37	31	I/O	General-purpose digital I/O / LCD segment output 6	
P2.7/S6					



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Terminal Functions (Continued)

TERMIN	AL				
NAME	DL NO.	RGZ NO.	I/O	DESCRIPTION	
P2.5/S8	39	33	I/O	General-purpose digital I/O / LCD segment output 8	
P2.4/S9	40	34	I/O	General-purpose digital I/O / LCD segment output 9	
P2.3/S10	41	35	I/O	General-purpose digital I/O / LCD segment output 10	
P2.2/S11	42	36	I/O	General-purpose digital I/O / LCD segment output 11	
P2.1/S12/SW1C	43	37	I/O	General-purpose digital I/O / LCD segment output 12 / Low resistance switch to V_{SS}	
P2.0/S13/SW0C	44	38	I/O	General-purpose digital I/O / LCD segment output 13 / Low resistance switch to V_{SS}	
COM0	45	39	0	Common output. COM0–COM3 are used for LCD backplanes.	
P5.2/COM1	46	40	I/O	General-purpose digital I/O / common output. COM0–COM3 are used for LCD backplanes.	
P5.3/COM2	47	41	I/O	General-purpose digital I/O / common output. COM0–COM3 are used for LCD backplanes.	
P5.4/COM3	48	42	I/O	General-purpose digital I/O / common output. COM0–COM3 are used for LCD backplanes.	
QFN Pad	NA	None	NA	QFN package pad connection to DV _{SS} is recommended.	



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short-form description

CPU

The MSP430 CPU has a 16-bit RISC architecture that is highly transparent to the application. All operations, other than program-flow instructions, are performed as register operations in conjunction with seven addressing modes for source operand and four addressing modes for destination operand.

The CPU is integrated with 16 registers that provide reduced instruction execution time. The register-to-register operation execution time is one cycle of the CPU clock.

Four of the registers, R0 to R3, are dedicated as program counter, stack pointer, status register, and constant generator respectively. The remaining registers are general-purpose registers.

Peripherals are connected to the CPU using data, address, and control buses, and can be handled with all instructions.

instruction set

The instruction set consists of 51 instructions with three formats and seven address modes. Each instruction can operate on word and byte data. Table 1 shows examples of the three types of instruction formats. Table 2 lists the address modes.



Table 1. Instruction Word Formats

Dual operands, source-destination	e.g., ADD R4,R5	R4 + R5> R5
Single operands, destination only	e.g., CALL R8	PC>(TOS), R8> PC
Relative jump, un/conditional	e.g., JNE	Jump-on-equal bit = 0

ADDRESS MODE	s	D	SYNTAX	EXAMPLE	OPERATION
Register	ullet	ullet	MOV Rs,Rd	MOV R10,R11	R10 —> R11
Indexed	•	•	MOV X(Rn),Y(Rm)	MOV 2(R5),6(R6)	M(2+R5)—> M(6+R6)
Symbolic (PC relative)	•	•	MOV EDE,TONI		M(EDE) —> M(TONI)
Absolute	•	•	MOV & MEM, & TCDAT		M(MEM) —> M(TCDAT)
Indirect	•		MOV @Rn,Y(Rm)	MOV @R10,Tab(R6)	M(R10) —> M(Tab+R6)
Indirect autoincrement	•		MOV @Rn+,Rm	MOV @R10+,R11	M(R10) —> R11 R10 + 2—> R10
Immediate	•		MOV #X,TONI	MOV #45,TONI	#45 —> M(TONI)

Table 2. Address Mode Descriptions

NOTE: S = source D = destination



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operating modes

The MSP430 has one active mode and five software selectable low-power modes of operation. An interrupt event can wake up the device from any of the five low-power modes, service the request, and restore back to the low-power mode on return from the interrupt program.

The following six operating modes can be configured by software:

- Active mode (AM)
 - All clocks are active
- Low-power mode 0 (LPM0)
 - CPU is disabled ACLK and SMCLK remain active, MCLK is available to modules FLL+ loop control remains active
- Low-power mode 1 (LPM1)
 - CPU is disabled ACLK and SMCLK remain active, MCLK is available to modules FLL+ loop control is disabled
- Low-power mode 2 (LPM2)
 - CPU is disabled MCLK, FLL+ loop control, and DCOCLK are disabled DCO's dc-generator remains enabled ACLK remains active
- Low-power mode 3 (LPM3)
 - CPU is disabled MCLK, FLL+ loop control, and DCOCLK are disabled DCO's dc-generator is disabled ACLK remains active
- Low-power mode 4 (LPM4)
 - CPU is disabled ACLK is disabled MCLK, FLL+ loop control, and DCOCLK are disabled DCO's dc-generator is disabled Crystal oscillator is stopped



interrupt vector addresses

The interrupt vectors and the power-up starting address are located in the address range 0FFFFh to 0FFE0h. The vector contains the 16-bit address of the appropriate interrupt-handler instruction sequence.

INTERRUPT SOURCE	INTERRUPT FLAG	SYSTEM INTERRUPT	WORD ADDRESS	PRIORITY
Power-Up External Reset Watchdog	WDTIFG	Reset	0FFFEh	15, highest
Flash Memory PC Out-of-Range (see Note 4)	KEYV (see Note 1)			
NMI Oscillator Fault Flash Memory Access Violation	NMIIFG (see Notes 1 and 3) OFIFG (see Notes 1 and 3) ACCVIFG (see Notes 1 and 3)	(Non)maskable (Non)maskable (Non)maskable	0FFFCh	14
			0FFFAh	13
SD16_A	SD16CCTLx SD16OVIFG, SD16CCTLx SD16IFG (see Notes 1 and 2)	Maskable	0FFF8h	12
			0FFF6h	11
Watchdog Timer	WDTIFG	Maskable	0FFF4h	10
			0FFF2h	9
			0FFF0h	8
			0FFEEh	7
Timer_A3	TACCR0 CCIFG0 (see Note 2)	Maskable	0FFECh	6
Timer_A3	TACCR1 CCIFG1 and TACCR2 CCIFG2, TAIFG (see Notes 1 and 2)	Maskable	0FFEAh	5
I/O Port P1 (Eight Flags)	P1IFG.0 to P1IFG.7 (see Notes 1 and 2)	Maskable	0FFE8h	4
DAC12	DAC12_0IFG (see Note 2)	Maskable	0FFE6h	3
			0FFE4h	2
I/O Port P2 (Eight Flags)	P2IFG.0 to P2IFG.7 (see Notes 1 and 2)	Maskable	0FFE2h	1
Basic Timer1	BTIFG	Maskable	0FFE0h	0, lowest

Table 3. Interrupt Sources	Flags and	Vectors of MSP	430EG42x0 Con	figuration
Table 5. Interrupt Sources	5, i lays, allu	VECTORS OF MISE	4301 04280 0011	nguration

NOTES: 1. Multiple source flags

2. Interrupt flags are located in the module.

3. (Non)maskable: the individual interrupt-enable bit can disable an interrupt event, but the general-interrupt enable cannot disable it.

4. A reset is generated if the CPU tries to fetch instructions from within the module register memory address range (0h–01FFh) or from within unused address ranges (MSP430FG4270, MSP430FG4260: from 0300h to 0BFFh and from 01100h to 07FFFh, MSP430FG4250: from 0300h to 0BFFh and from 01100h to 08FFFh).

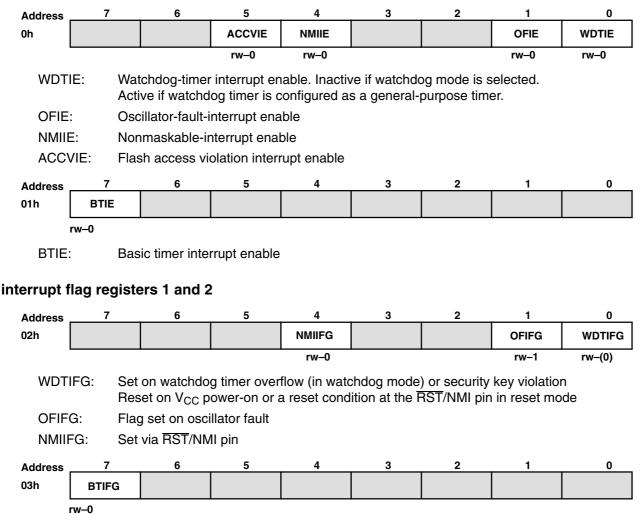


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special function registers (SFRs)

The MSP430 SFRs are located in the lowest address space and are organized as byte-mode registers. SFRs should be accessed with byte instructions.

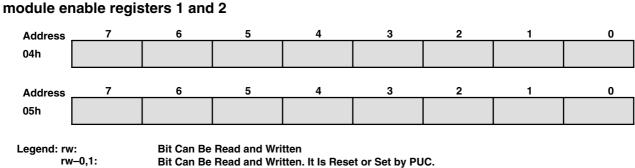
interrupt enable registers 1 and 2



BTIFG: Basic timer flag



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rw–0,1: rw–(0,1):

Bit Can Be Read and Written. It Is Reset or Set by PUC. Bit Can Be Read and Written. It Is Reset or Set by POR.

SFR Bit Not Present in Device

memory organization

		MSP430FG4250	MSP430FG4260	MSP430FG4270
Memory	Size	16KB	24KB	32KB
Main: interrupt vector	Flash	0FFFFh – 0FFE0h	0FFFFh – 0FFE0h	0FFFFh – 0FFE0h
Main: code memory	Flash	0FFFFh – 0C000h	0FFFFh – 0A000h	0FFFFh – 08000h
Information memory	Size	256 Byte	256 Byte	256 Byte
	Flash	010FFh – 01000h	010FFh – 01000h	010FFh – 01000h
Boot memory	Size	1KB	1KB	1KB
	ROM	0FFFh – 0C00h	0FFFh – 0C00h	0FFFh – 0C00h
RAM	Size	256 Byte 02FFh – 0200h	256 Byte 02FFh – 0200h	256 Byte 02FFh – 0200h
Peripherals	16-bit	01FFh – 0100h	01FFh – 0100h	01FFh – 0100h
	8-bit	0FFh – 010h	0FFh – 010h	0FFh – 010h
	8-bit SFR	0Fh – 00h	0Fh – 00h	0Fh – 00h

bootstrap loader (BSL)

The MSP430 BSL enables users to program the flash memory or RAM using a UART serial interface. Access to the MSP430 memory via the BSL is protected by user-defined password. For complete description of the features of the BSL and its implementation, see the application report *Features of the MSP430 Bootstrap Loader*, literature number SLAA089.

BSL Function	DL Package Pins	RGZ Package Pins
Data Transmit	28 - P1.0	22 - P1.0
Data Receive	27 - P1.1	21 - P1.1

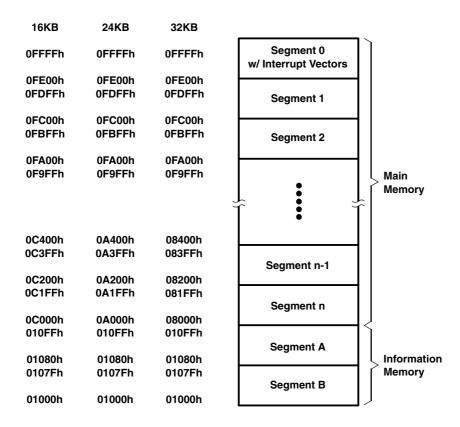


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flash memory

The flash memory can be programmed via the JTAG port, the bootstrap loader, or in-system by the CPU. The CPU can perform single-byte and single-word writes to the flash memory. Features of the flash memory include:

- Flash memory has n segments of main memory and two segments of information memory (A and B) of 128 bytes each. Each segment in main memory is 512 bytes in size.
- Segments 0 to n may be erased in one step, or each segment may be individually erased.
- Segments A and B can be erased individually, or as a group with segments 0 to n. Segments A and B are also called *information memory*.
- New devices may have some bytes programmed in the information memory (needed for test during manufacturing). The user should perform an erase of the information memory prior to the first use.





peripherals

Peripherals are connected to the CPU through data, address, and control buses and can be handled using all instructions. For complete module descriptions, refer to the *MSP430x4xx Family User's Guide*, literature number SLAU056.

oscillator and system clock

The clock system in the MSP430FG42x0 family of devices is supported by the FLL+ module, which includes support for a 32768-Hz watch crystal oscillator, an internal digitally-controlled oscillator (DCO) and a high-frequency crystal oscillator. The FLL+ clock module is designed to meet the requirements of both low system cost and low-power consumption. The FLL+ features digital frequency locked loop (FLL) hardware that, in conjunction with a digital modulator, stabilizes the DCO frequency to a programmable multiple of the watch crystal frequency. The internal DCO provides a fast turn-on clock source and stabilizes in less than 6 µs. The FLL+ module provides the following clock signals:

- Auxiliary clock (ACLK), sourced from a 32768-Hz watch crystal or a high-frequency crystal
- Main clock (MCLK), the system clock used by the CPU
- Sub-Main clock (SMCLK), the sub-system clock used by the peripheral modules
- ACLK/n, the buffered output of ACLK, ACLK/2, ACLK/4, or ACLK/8

brownout

The brownout circuit is implemented to provide the proper internal reset signal to the device during power-on and power-off. The CPU begins code execution after the brownout circuit releases the device reset. However, V_{CC} may not have ramped to $V_{CC(min)}$ at that time. The user must ensure the default FLL+ settings are not changed until V_{CC} reaches $V_{CC(min)}$.

digital I/O

There are four 8-bit I/O ports implemented—ports P1, P2, P5, and P6:

- All individual I/O bits are independently programmable.
- Any combination of input, output, and interrupt conditions is possible.
- Edge-selectable interrupt input capability for all the eight bits of ports P1 and P2.
- Read/write access to port-control registers is supported by all instructions.

Basic Timer1

Basic Timer1 has two independent 8-bit timers that can be cascaded to form a 16-bit timer/counter. Both timers can be read and written by software. Basic Timer1 can be used to generate periodic interrupts.

LCD driver with regulated charge pump

The LCD_A driver generates the segment and common signals required to drive an LCD display. The LCD_A controller has dedicated data memory to hold segment drive information. Common and segment signals are generated as defined by the mode. Static, 2–MUX, 3–MUX, and 4–MUX LCDs are supported by this peripheral. The module can provide a LCD voltage independent of the supply voltage via an integrated charge pump. Furthermore, it is possible to control the level of the LCD voltage and thus contrast in software.

watchdog timer

The primary function of the watchdog timer (WDT+) module is to perform a controlled system restart after a software problem occurs. If the selected time interval expires, a system reset is generated. If the watchdog function is not needed in an application, the module can be configured as an interval timer and can generate interrupts at selected time intervals.



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Timer_A3

Timer_A3 is a 16-bit timer/counter with three capture/compare registers. Timer_A3 can support multiple capture/compares, PWM outputs, and interval timing. Timer_A3 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

		٦	Timer_A3 Signa	al Connectio	ns			
Input Pir	n Number	Device Input	Module	Module	Module Output	Output Pin Number		
DL	RGZ	Signal	Input Name	Block	Signal	DL	RGZ	
23 - P1.5	17 - P1.5	TACLK	TACLK					
		ACLK	ACLK	T				
		SMCLK	SMCLK	Timer	NA			
23 - P1.5	17 - P1.5	TACLK	INCLK					
28 - P1.0	22 - P1.0	TA0	CCI0A			28 - P1.0	22 - P1.0	
27 - P1.1	21 - P1.1	TA0	CCI0B	0000	ТАО			
		DV _{SS}	GND	CCR0				
		DV _{CC}	V _{CC}					
26 - P1.2	20 - P1.2	TA1	CCI1A			26 - P1.2	20 - P1.2	
26 - P1.2	20 - P1.2	TA1	CCI1B	0054	TA			
		DV _{SS}	GND	CCR1	TA1			
		DV _{CC}	V _{CC}					
25 - P1.3	19 - P1.3	TA2	CCI2A			25 - P1.3	19 - P1.3	
		ACLK (internal)	CCI2B	0.000	TA2			
		DV _{SS}	GND	CCR2				
		DV _{CC}	V _{CC}					

SD16_A

The SD16_A module supports 16-bit analog-to-digital conversions. The module implements a 16-bit sigma-delta core and reference generator. In addition to external analog inputs, an internal V_{CC} sense and temperature sensor are also available.

DAC12

The DAC12 module is a 12-bit, R-ladder, voltage output DAC. The DAC12 may be used in 8- or 12-bit mode.



operational amplifier (OA)

The MSP430FG42x0 has two configurable low-current general-purpose operational amplifiers. Each OA input and output terminal is software-selectable and offers a flexible choice of connections for various applications. The OAs primarily support front-end analog signal conditioning prior to analog-to-digital conversion.

	OA Signal Connections								
Input Pin Number		Device Input	Module	Module	Module Output	Output Pi	n Number		
DL	RGZ	Signal	Input Name	Block	Signal	DL	RGZ		
22 - P1.6	16 - P1.6	OA010	OA010			13 - P6.0	7 - P6.0		
17 - P6.4	11 - P6.4	OA0I1	OA0I1	0.40	OA0O				
18 - P6.5	12 - P6.5	OA012	OA012	OA0					
14 - P6.1	8 - P6.1	OA0FB	OA0FB						
24 - P1.4	18 - P1.4	OA1I0	OA1I0			15 - P6.0	9 - P6.0		
19 - P6.6	13 - P6.6	OA1I1	OA1I1						
20 - P6.7	14 - P6.7	OA1I2	OA1I2	OA1	OA1O				
16 - P6.1	10 - P6.1	OA1FB	OA1FB						



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peripheral file map

	PERIPHERALS WITH WORD ACCESS		
Watchdog	Watchdog timer control	WDTCTL	0120h
Timer_A3	Capture/compare register 2	TACCR2	0176h
	Capture/compare register 1	TACCR1	0174h
	Capture/compare register 0	TACCR0	0172h
	Timer_A register	TAR	0170h
	Capture/compare control 2	TACCTL2	0166h
	Capture/compare control 1	TACCTL1	0164h
	Capture/compare control 0	TACCTL0	0162h
	Timer_A control	TACTL	0160h
	Timer_A interrupt vector	TAIV	012Eh
Flash	Flash control 3	FCTL3	012Ch
	Flash control 2	FCTL2	012Ah
	Flash control 1	FCTL1	0128h
DAC12	DAC12_0 data	DAC12_0DAT	01C8h
	DAC12_0 control	DAC12_0CTL	01C0h
SD16_A	General control	SD16CTL	0100h
(see also	Channel 0 control	SD16CCTL0	0102h
Peripherals With Byte Access)	Interrupt vector word register	SD16IV	0110h
Dyle Access)	Channel 0 conversion memory	SD16MEM0	0112h
	PERIPHERALS WITH BYTE ACCESS		•
OA/GND Switches	Switch control register	SWCTL	0CFh
OA1	Operational amplifier 1 control register 1	OA1CTL1	0C3h
	Operational amplifier 1 control register 0	OA1CTL0	0C2h
OA0	Operational amplifier 0 control register 1	OA0CTL1	0C1h
	Operational amplifier 0 control register 0	OA0CTL0	0C0h
SD16_A	Channel 0 input control	SD16INCTL0	0B0h
(see also: Peripherals with	Analog enable	SD16AE	0B7h
Word Access)			
LCD_A	LCD voltage control 1	LCDAVCTL1	0AFh
	LCD voltage control 0	LCDAVCTL0	0AEh
	LCD voltage port control 1	LCDAPCTL1	0ADh
	LCD voltage port control 0	LCDAPCTL0	0ACh
	LCD memory 20	LCDM20	0A4h
	:	:	:
	LCD memory 16	LCDM16	0A0h
	LCD memory 15	LCDM15	09Fh
	:	:	:
	LCD memory 1	LCDM1	091h
	LCD control and mode	LCDACTL	090h



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	PERIPHERALS WITH BYTE ACCESS (C	ONTINUED)	
FLL+ Clock	FLL+ Control 1	FLL_CTL1	054h
	FLL+ Control 0	FLL_CTL0	053h
	System clock frequency control	SCFQCTL	052h
	System clock frequency integrator	SCFI1	051h
	System clock frequency integrator	SCFI0	050h
Basic Timer1	BT counter 2	BTCNT2	047h
	BT counter 1	BTCNT1	046h
	BT control	BTCTL	040h
Port P6	Port P6 selection	P6SEL	037h
	Port P6 direction	P6DIR	036h
	Port P6 output	P6OUT	035h
	Port P6 input	P6IN	034h
Port P5	Port P5 selection	P5SEL	033h
	Port P5 direction	P5DIR	032h
	Port P5 output	P5OUT	031h
	Port P5 input	P5IN	030h
Port P2	Port P2 selection	P2SEL	02Eh
	Port P2 interrupt enable	P2IE	02Dh
	Port P2 interrupt-edge select	P2IES	02Ch
	Port P2 interrupt flag	P2IFG	02Bh
	Port P2 direction	P2DIR	02Ah
	Port P2 output	P2OUT	029h
	Port P2 input	P2IN	028h
Port P1	Port P1 selection	P1SEL	026h
	Port P1 interrupt enable	P1IE	025h
	Port P1 interrupt-edge select	P1IES	024h
	Port P1 interrupt flag	P1IFG	023h
	Port P1 direction	P1DIR	022h
	Port P1 output	P1OUT	021h
	Port P1 input	P1IN	020h
Special functions	SFR module enable 2	ME2	005h
	SFR module enable 1	ME1	004h
	SFR interrupt flag 2	IFG2	003h
	SFR interrupt flag 1	IFG1	002h
	SFR interrupt enable 2	IE2	001h
	SFR interrupt enable 1	IE1	000h

peripheral file map (continued)



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absolute maximum ratings over operating free-air temperature (unless otherwise noted)[†]

Voltage applied at V _{CC} to V _{SS}	–0.3 V to 4.1 V
Voltage applied to any pin (see Note 1)	. –0.3 V to V _{CC} + 0.3 V
Diode current at any device terminal .	±2 mA
Storage temperature, T _{stg} : Unprogrammed device	–55°C to 150°C
Programmed device	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltages referenced to V_{SS}. The JTAG fuse-blow voltage, V_{FB}, is allowed to exceed the absolute maximum rating. The voltage is applied to the TDI/TCLK pin when blowing the JTAG fuse.

recommended operating conditions

			MIN	NOM MAX	UNIT
Supply voltage during program execution (see V_{CC} (AV _{CC} = DV _{CC} = V _{CC})	e Note 1),		1.8	3.6	v
Supply voltage during flash memory programming (see Note 1), V_{CC} (AV _{CC} = DV _{CC} = V _{CC})		2.5	3.6	v	
Supply voltage, V_{SS} (AV _{SS} = DV _{SS} = V _{SS})			0	0	V
Operating free-air temperature, T _A	Operating free-air temperature, T _A		-40	85	°C
	LF selected, XTS_FLL=0	Watch crystal		32.768	
LFXT1 crystal frequency, f _(LFXT1) (see Note 2)	XT1 selected, XTS_FLL=1	Ceramic resonator	450	8000	kHz
	XT1 selected, XTS_FLL=1	Crystal	1000	8000	
		V _{CC} = 1.8 V	DC	4.15	N411-
Processor frequency (signal MCLK), f _(System)		V _{CC} = 3.6 V	DC	8	MHz

NOTES: 1. It is recommended to power AV_{CC} and DV_{CC} from the same source. A maximum difference of 0.3 V between AV_{CC} and DV_{CC} can be tolerated during power up and operation.

2. In LF mode, the LFXT1 oscillator requires a watch crystal. In XT1 mode, LFXT1 accepts a ceramic resonator or a crystal.

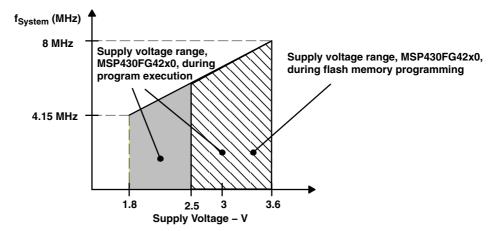


Figure 1. Frequency vs Supply Voltage, Typical Characteristic



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONE	DITIONS	MIN	NOM	MAX	UNIT	
I _(AM)	Active mode (see Note 1), $f_{(MCLK)} = f_{(SMCLK)} = 1$ MHz, $f_{(ACLK)} = 32,768$ Hz XTS=0, SELM=(0,1)	$T_A = -40^{\circ}C$ to $85^{\circ}C$	$V_{CC} = 2.2 V$ $V_{CC} = 3 V$		250 400	370 520	μA	
I _(LPM0)	Low-power mode (LPM0) (see Note 1 and Note 4)	$T_A = -40^{\circ}C$ to $85^{\circ}C$	$V_{CC} = 2.2 V$ $V_{CC} = 3 V$		55 95	70 110	μA	
I _(LPM2)	Low-power mode (LPM2), $f_{(MCLK)} = f_{(SMCLK)} = 0$ MHz,	C_{LK} = f _(SMCLK) = 0 MHz, C_{LK} = 32,768 Hz, SCG0 = 0 $T_A = -40^{\circ}$ C to 85°C $V_{CC} = 2.2 V$			11	14	μA	
	t _(ACLK) = 32,768 Hz, SCG0 = 0 (see Note 2 and Note 4)		$V_{CC} = 3 V$		17	22	P. 1	
		$T_A = -40^{\circ}C$			1.0	2.0		
	Low-power mode (LPM3),	$T_A = 25^{\circ}C$			1.1	2.0		
	$f_{(MCLK)} = f_{(SMCLK)} = 0$ MHz,	$T_A = 60^{\circ}C$	V _{CC} = 2.2 V		2.0	3.0		
	f _(ACLK) = 32,768 Hz, SCG0 = 1 Basic Timer1 enabled, ACLK selected	$T_A = 85^{\circ}C$			3.5	6.0	۸	
(LPM3)	LCD_A enabled, LCDCPEN = 0	$T_A = -40^{\circ}C$			1.8	2.8	μA	
	(static mode, $f_{LCD} = f_{(ACLK)}/32$), (see Note 2, Note 3, and Note 4)	$T_A = 25^{\circ}C$	Voo - 3 V		1.6	2.7		
		(see Note 2, Note 3, and Note 4) $T_A = 60^{\circ}C$	V _{CC} = 3 V		2.5	3.5		
		$T_A = 85^{\circ}C$				4.2	7.5	
	Low-power mode (LPM3),	$T_A = -40^{\circ}C$			2.5	3.5		
	$f_{(MCLK)} = f_{(SMCLK)} = 0$ MHz,	$T_A = 25^{\circ}C$	V _{CC} = 2.2 V		2.5	3.5		
	f _(ACLK) = 32,768 Hz, SCG0 = 1 Basic Timer1 enabled, ACLK selected	$T_A = 85^{\circ}C$			3.8	6.0		
I _(LPM3)	LCD_A enabled, LCDCPEN = 0	$T_A = -40^{\circ}C$			2.9	4.0	μA	
	(4-mux mode, f _{LCD} = f _(ACLK) /32),	$T_A = 25^{\circ}C$	$V_{CC} = 3 V$		2.9	4.0		
	(see Note 2, Note 3, and Note 4)	$T_A = 85^{\circ}C$			4.4	7.5		
		$T_A = -40^{\circ}C$			0.1	0.5		
		$T_A = 25^{\circ}C$			0.1	0.5		
	(ACLR) = 0.112, 0000 = 1	$T_A = 60^{\circ}C$	V _{CC} = 2.2 V		0.7	1.1		
		$T_A = 85^{\circ}C$			1.7	3.0		
(LPM4)		$T_A = -40^{\circ}C$			0.1	0.8	μ A	
	(see Note 2 and Note 4)	$T_A = 25^{\circ}C$	V2V		0.1	0.8		
		$T_A = 60^{\circ}C$	$V_{CC} = 3 V$		0.8	1.2		
		T _A = 85°C			1.9	3.5		

supply current into AV_{CC} + DV_{CC} excluding external current

NOTES: 1. Timer_A is clocked by $f_{(DCOCLK)} = f_{(DCO)} = 1$ MHz. All inputs are tied to 0 V or to V_{CC}. Outputs do not source or sink any current. 2. All inputs are tied to 0 V or to V_{CC}. Outputs do not source or sink any current.

3. The LPM3 currents are characterized with a Micro Crystal CC4V-T1A (9 pF) crystal and OSCCAPx = 01h.

4. Current for brownout included.

current consumption of active mode versus system frequency

 $I_{(AM)} = I_{(AM)} [1 \text{ MHz}] \times f_{(System)} [MHz]$

current consumption of active mode versus supply voltage

 $I_{(AM)} = I_{(AM) [3 V]} + 175 \ \mu A/V \times (V_{CC} - 3 V)$



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

Schmitt-trigger inputs – Ports P1, P2, P5, and P6; RST/NMI; JTAG: TCK, TMS, TDI/TCLK, TDO/TDI

	PARAMETER	TEST CONDITIONS	MIN	ΤΥΡ ΜΑΧ	UNIT
	Desitive asian insult threads and walks as	V _{CC} = 2.2 V	1.1	1.55	v
V _{IT+}	Positive-going input threshold voltage	$V_{CC} = 3 V$	1.5	1.98	v
v		V _{CC} = 2.2 V	0.4	0.9	v
V _{IT-}	Negative-going input threshold voltage	V _{CC} = 3 V	0.9	1.3	v
v	Input voltage hystoregie $(V = V_{i})$	V _{CC} = 2.2 V	0.3	1.1	v
V _{hys}	Input voltage hysteresis (V _{IT+} – V _{IT-})	$V_{CC} = 3 V$	0.5	1	v

inputs Px.x, TAx

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT	
	Eutomal interrupt timing	Port P1, P2: P1.x to P2.x, external trigger signal	2.2 V	62				
t _(int)	External interrupt timing	for the interrupt flag, (see Note 1)	3 V	50			ns	
	Time of Alexandron Marine	TAO TAI TAO	2.2 V	62				
t _(cap)	Timer_A capture timing	TA0, TA1, TA2	3 V	50			ns	
4	Timer_A clock frequency		2.2 V			8	MHz	
f _(TAext)	externally applied to pin	TACLK, INCLK: $t_{(H)} = t_{(L)}$	3 V			10	IVITIZ	
			2.2 V			8		
f _(TAint)	Timer_A clock frequency	SMCLK or ACLK signal selected	3 V			10	MHz	

NOTES: 1. The external signal sets the interrupt flag every time the minimum t_(int) parameters are met. It may be set even with trigger signals shorter than t_(int).

leakage current - ports P1, P2, P5, and P6 (see Note 1)

	PARAMETER		TEST CONDITIONS			TYP	MAX	UNIT
I _{lkg(Px.y)}	Leakage current	Port Px	V _(Px.y) (see Note 2)	$V_{CC} = 2.2 \text{ V/3 V}$			±50	nA

NOTES: 1. The leakage current is measured with V_{SS} or V_{CC} applied to the corresponding pin(s), unless otherwise noted.

2. The port pin must be selected as input.



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

outputs - ports P1, P2, P5, and P6

	PARAMETER	TES	T CONDITIONS		MIN	TYP MAX	UNIT
		$I_{OH(max)} = -1.5 \text{ mA},$	V _{CC} = 2.2 V,	See Note 1	V _{CC} -0.25	V _{CC}	
	I Bala Jacob andre de calla an	$I_{OH(max)} = -6 \text{ mA},$	V _{CC} = 2.2 V,	See Note 2	V _{CC} -0.6	V _{CC}	
V _{OH}	High-level output voltage	$I_{OH(max)} = -1.5 \text{ mA},$	V _{CC} = 3 V,	See Note 1	V _{CC} -0.25	V _{CC}	V
		$I_{OH(max)} = -6 \text{ mA},$	V _{CC} = 3 V,	See Note 2	V _{CC} -0.6	V _{CC}	
		$I_{OL(max)} = 1.5 \text{ mA},$	$V_{CC} = 2.2 V,$	See Note 1	V _{SS}	V _{SS} +0.25	
		I _{OL(max)} = 6 mA,	V _{CC} = 2.2 V,	See Note 2	V _{SS}	V _{SS} +0.6	v
VOL		$I_{OL(max)} = 1.5 \text{ mA},$	V _{CC} = 3 V,	See Note 1	V _{SS}	V _{SS} +0.25	v
		$I_{OL(max)} = 6 \text{ mA},$	V _{CC} = 3 V,	See Note 2	V _{SS}	V _{SS} +0.6	

NOTES: 1. The maximum total current, I_{OH(max)} and I_{OL(max)}, for all outputs combined, should not exceed ±12 mA to satisfy the maximum specified voltage drop.

2. The maximum total current, I_{OH(max)} and I_{OL(max)}, for all outputs combined, should not exceed ±48 mA to satisfy the maximum specified voltage drop.

output frequency

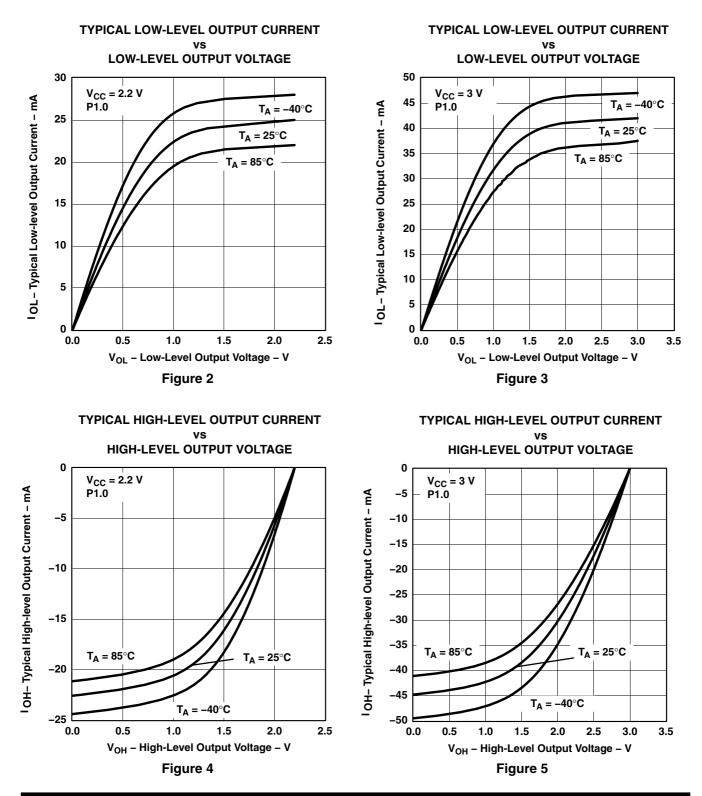
	PARAMETER	TEST CONDITIONS			ТҮР	MAX	UNIT
f _(Px.y)	$(x=1,2,5,6,0\leq y\leq 7)$	$C_L = 20 \text{ pF},$ $I_L = \pm 1.5 \text{ mA}$	$V_{CC} = 2.2 V / 3 V$	DC		f _{System}	MHz
f _(MCLK)	P1.1/TA0/MCLK	C _L = 20 pF				f _{System}	MHz
		P1.1/TA0/MCLK,	$f_{(MCLK)} = f_{(XT1)}$	40%		60%	
t _(Xdc)	Duty cycle of output frequency	$C_L = 20 \text{ pF},$ $V_{CC} = 2.2 \text{ V} / 3 \text{ V}$	$f_{(MCLK)} = f_{(DCOCLK)}$	50%– 15 ns	50%	50%+ 15 ns	



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

outputs - ports P1, P2, P5, and P6 (continued)





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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

wake-up LPM3

PARAMETER	TEST	MIN	TYP	MAX	UNIT	
	f = 1 MHz				6	
t _{d(LPM3)} Delay time	f = 2 MHz	V _{CC} = 2.2 V/3 V			6	μs
	f = 3 MHz				6	

RAM

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VRAMh	CPU halted (see Note 1)	1.6			V
	a de la la la la companya de la DAM accessione		and Min		

NOTE 1: This parameter defines the minimum supply voltage when the data in program memory RAM remain unchanged. No program execution should take place during this supply voltage condition.

LCD_A

	PARAMETER	TEST CONDITIONS	VCC	MIN	ТҮР	MAX	UNIT
V _{CC(LCD)}	Supply voltage	Charge pump enabled (LCDCPEN = 1, VLCDx > 0000)		2.2		3.6	v
C _{LCD}	Capacitor on LCDCAP (see Note 1)	Charge pump enabled (LCDCPEN = 1, VLCDx > 0000)		4.7			μF
I _{CC(LCD)}	Average supply current (see Note 2)	$\begin{array}{l} V_{LCD(typ)}{=}3V, LCDCPEN = 1,\\ VLCDx{=}\ 1000, \ all \ segments \ on \\ f_{LCD}{=}\ f_{ACLK}/32\\ no \ LCD \ connected \ (see \ Note \ 3) \\ T_{A} = 25^{\circ}C \end{array}$	2.2 V		3.8		μA
f _{LCD}	LCD frequency					1.1	kHz
		VLCDx = 0000			VCC		
		VLCDx = 0001			2.60		
		VLCDx = 0010			2.66		
		VLCDx = 0011			2.72		
		VLCDx = 0100			2.78		
		VLCDx = 0101			2.84		
		VLCDx = 0110			2.90		
		VLCDx = 0111			2.96		
V _{LCD}	LCD voltage	VLCDx = 1000			3.02		v
		VLCDx = 1001			3.08		
		VLCDx = 1010			3.14		
		VLCDx = 1011			3.20		
		VLCDx = 1100			3.26		
		VLCDx = 1101			3.32		
		VLCDx = 1110			3.38		
		VLCDx = 1111			3.44	3.60	
R _{LCD}	LCD driver output impedance	V_{LCD} = 3V, LCDCPEN = 1, VLCDx = 1000, I _{LOAD} = ±10 µA	2.2 V			10	kΩ

NOTES: 1. Enabling the internal charge pump with an external capacitor smaller than the minimum specified might damage the device.

2. Refer to the supply current specifications I(LPM3) for additional current specifications with the LCD_A module active.

3. Connecting an actual display will increase the current consumption depending on the size of the LCD.



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

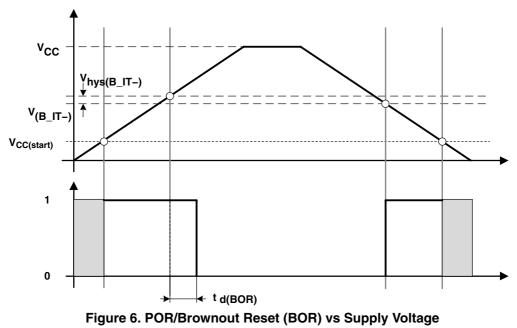
POR/brownout reset (BOR) (see Note 1)

PARA	METER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
t _{d(BOR)}					2000	μs
V _{CC(start)}		$dV_{CC}/dt \le 3 V/s$ (see Figure 6)		$0.7 \times V_{(B_IT-)}$		V
V _(B_IT-)	Brownout	$dV_{CC}/dt \le 3$ V/s (see Figure 6 through Figure 8)			1.71	V
V _{hys(B_IT-)}	(see Note 2)	$dV_{CC}/dt \le 3 V/s$ (see Figure 6)	70	130	180	mV
t _(reset)		Pulse length needed at $\overrightarrow{\text{RST}}$ /NMI pin to accepted reset internally, V_{CC} = 2.2 V/3 V	2			μs

NOTES: 1. The current consumption of the brownout module is already included in the I_{CC} current consumption data. The voltage level $V_{(B_{-}|T_{-})} + V_{hys(B_{-}|T_{-})}$ is $\leq 1.8V$.

During power up, the CPU begins code execution following a period of t_{d(BOR)} after V_{CC} = V_{(B_IT-}) + V_{hys(B_IT-}). The default FLL+ settings must not be changed until V_{CC} ≥ V_{CC(min)}, where V_{CC(min)} is the minimum supply voltage for the desired operating frequency. See the *MSP430x4xx Family User's Guide* (SLAU056) for more information on the brownout.

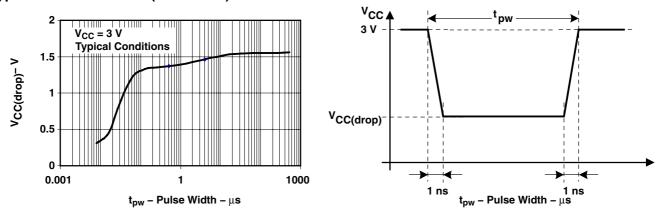
typical characteristics





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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)



typical characteristics (continued)



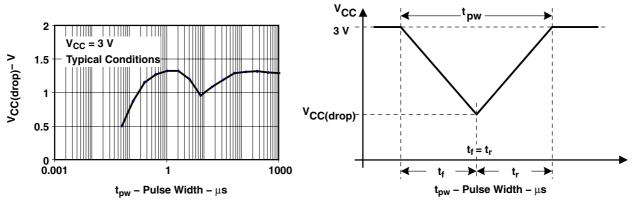


Figure 8. V_{CC(drop)} Level With a Triangle Voltage Drop to Generate a POR/Brownout Signal



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted)

DCO

PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
f(DCOCLK)	$N_{(DCO)}$ =01Eh, FN_8=FN_4=FN_3=FN_2=0, D = 2, DCOPLUS= 0, f _{Crystal} = 32.768 kHz	2.2 V/3 V		1		MHz
,		2.2 V	0.3	0.65	1.25	N 41 1-
f(DCO=2)	FN_8 = FN_4 = FN_3 = FN_2 = 0, DCOPLUS = 1	3 V	0.3	0.7	1.3	MHz
		2.2 V	2.5	5.6	10.5	N 41 1-
f(DCO=27)	FN_8 = FN_4 = FN_3 = FN_2 = 0, DCOPLUS = 1	3 V	2.7	6.1	11.3	MHz
f	FN 8 = FN 4 = FN 3 = 0, FN 2 = 1, DCOPLUS = 1	2.2 V	0.7	1.3	2.3	MHz
f _(DCO=2)	$FN_6 = FN_4 = FN_3 = 0$, $FN_2 = 1$, DEOPLOS = 1	3 V	0.8	1.5	2.5	
£	FN 8 = FN 4 = FN 3 = 0, FN 2 = 1, DCOPLUS = 1	2.2 V	5.7	10.8	18	MHz
f _(DCO=27)	$FN_6 = FN_4 = FN_3 = 0$, $FN_2 = 1$, DEOPLOS = 1	3 V	6.5	12.1	20	
f	FN_8 = FN_4 = 0, FN_3 = 1, FN_2 = x, DCOPLUS = 1	2.2 V	1.2	2	3	MHz
f _(DCO=2)	$FN_{6} = FN_{4} = 0$, $FN_{3} = 1$, $FN_{2} = x$, $DCOPLOS = 1$	3 V	1.3	2.2	3.5	IVITZ
4		2.2 V	9	15.5	25	MHz
f(DCO=27)	FN_8 = FN_4 = 0, FN_3 = 1, FN_2 = x, DCOPLUS = 1	3 V	10.3	17.9	28.5	IVITZ
£	FN 8 = 0, FN 4 = 1, FN 3 = FN 2 = x, DCOPLUS = 1	2.2 V	1.8	2.8	4.2	MHz
f _(DCO=2)	$FN_{0} = 0, FN_{4} = 1, FN_{3} = FN_{2} = 2, DOOFLOS = 1$	3 V	2.1	3.4	5.2	
£		2.2 V	13.5	21.5	33	MHz
f _(DCO=27)	FN_8 = 0, FN_4 = 1, FN_3 = FN_2 = x, DCOPLUS = 1	3 V	16	26.6	41	IVITZ
4		2.2 V	2.8	4.2	6.2	MHz
f _(DCO=2)	FN_8 = 1, FN_4 = FN_3 = FN_2 = x, DCOPLUS = 1	3 V	4.2	6.3	9.2	IVITZ
4		2.2 V	21	32	46	MHz
f(DCO=27)	FN_8= 1, FN_4 = FN_3 = FN_2 = x, DCOPLUS = 1	3 V	30	46	70	IVITZ
<u> </u>	Step size between adjacent DCO taps:	$1 < TAP \le 20$	1.06		1.11	
S _n	$S_n = f_{DCO(Tap n+1)} / f_{DCO(Tap n)}$ (see Figure 10 for taps 21 to 27)	TAP = 27	1.07		1.17	
	Temperature drift, N _(DCO) = 01Eh, FN_8 = FN_4 = FN_3 = FN_2 = 0,	2.2 V	-0.2	-0.3	-0.4	%/°C
Dt	D = 2, DCOPLUS = 0 (see Note 2)	3 V	-0.2	-0.3	-0.4	70/ ° U
D _V	Drift with V _{CC} variation, N _(DCO) = 01Eh, FN_8 = FN_4 = FN_3 = FN_2 = 0, D = 2, DCOPLUS = 0		0	5	15	%/V

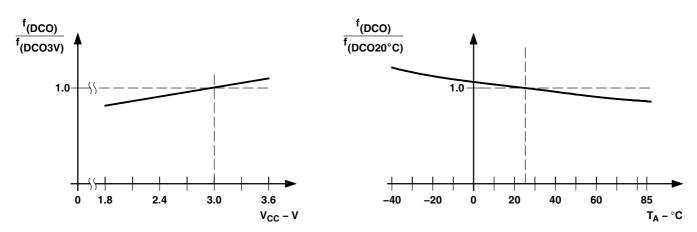


Figure 9. DCO Frequency vs Supply Voltage V_{CC} and vs Ambient Temperature



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

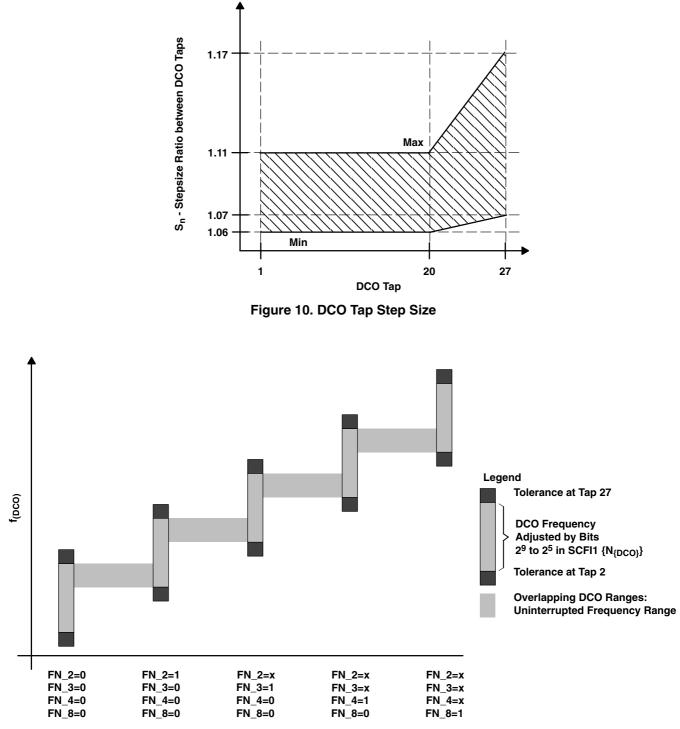


Figure 11. Five Overlapping DCO Ranges Controlled by FN_x Bits



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted)

crystal oscillator, LFXT1 oscillator (see Notes 1 and 2)

	PARAMETER	TEST CONDITIONS	MIN TYP MAX	UNIT
		OSCCAPx = 0h, V _{CC} = 2.2 V / 3 V	0	
•	Integrated input capacitance	OSCCAPx = 1h, V _{CC} = 2.2 V / 3 V	10	
C _{XIN}	(see Note 4)	OSCCAPx = 2h, V _{CC} = 2.2 V / 3 V	14	pF
		OSCCAPx = 3h, V _{CC} = 2.2 V / 3 V	18	
		OSCCAPx = 0h, V _{CC} = 2.2 V / 3 V	0	
•	Integrated output capacitance	OSCCAPx = 1h, V _{CC} = 2.2 V / 3 V	10	_
C _{XOUT}	(see Note 4)	OSCCAPx = 2h, V _{CC} = 2.2 V / 3 V	14	pF
		OSCCAPx = 3h, V _{CC} = 2.2 V / 3 V	18	
V _{IL}			V _{SS} 0.2×V _{CC}	
V _{IH}	Input levels at XIN	V _{CC} = 2.2 V/3 V (see Note 3)	0.8×V _{CC} V _{CC}	V

NOTES: 1. The parasitic capacitance from the package and board may be estimated to be 2 pF. The effective load capacitor for the crystal is $(C_{XIN \times C_{XOUT}}) / (C_{XIN} + C_{XOUT})$. This is independent of XTS_FLL.

2. To improve EMI on the low-power LFXT1 oscillator, particularly in the LF mode (32 kHz), the following guidelines should be observed.

- Keep as short of a trace as possible between the 'FG42x0 and the crystal.

- Design a good ground plane around the oscillator pins.

- Prevent crosstalk from other clock or data lines into oscillator pins XIN and XOUT.
- Avoid running PCB traces underneath or adjacent to the XIN and XOUT pins.
- Use assembly materials and praxis to avoid any parasitic load on the oscillator XIN and XOUT pins.
- If conformal coating is used, ensure that it does not induce capacitive/resistive leakage between the oscillator pins.
- Do not route the XOUT line to the JTAG header to support the serial programming adapter as shown in other documentation. This signal is no longer required for the serial programming adapter.
- 3. Applies only when using an external logic-level clock source. XTS_FLL must be set. Not applicable when using a crystal or resonator.
- 4. External capacitance is recommended for precision real-time clock applications, OSCCAPx = 0h.



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

	PARAMETER	TE	ST CONDITIONS	V _{CC}	MIN	ТҮР	MAX	UNIT
AV _{CC}	Analog supply voltage	$AV_{CC} = DV_{CC}$ $AV_{SS} = DV_{SS} = 0V$			2.5		3.6	V
		SD16LP = 0,	SD16BUFx = 00, GAIN: 1,2			650	950	
		$f_{SD16} = 1 \text{ MHz},$	SD16BUFx = 00, GAIN: 4,8,16			730	1100	
		SD16OSR = 256	SD16BUFx = 00, GAIN: 32			1050	1550	
	Analog supply	SD16LP = 1,	SD16BUFx = 00, GAIN: 1			620	930	
I _{SD16}	current including internal reference	f _{SD16} = 0.5 MHz, SD16OSR = 256	SD16BUFx = 00, GAIN: 32	3 V		700	1060	μA
		SD16LP = 0,	SD16BUFx = 01, GAIN: 1			850		
		$f_{SD16} = 1 \text{ MHz},$	SD16BUFx = 10, GAIN: 1			1130		
		SD16OSR = 256	SD16BUFx = 11, GAIN: 1			1130		
	Analog front-end	SD16LP = 0 (Low p	oower mode disabled)	0.1/	0.03	1	1.1	N 41 1-
f _{SD16}	input clock frequency	SD16LP = 1 (Low p	oower mode enabled)	3 V	0.03	0.5		MHz

SD16_A, power supply and recommended operating conditions

SD16_A, input range

I	PARAMETER	TEST CO	ONDITIONS	V _{CC}	MIN	ТҮР	MAX	UNIT
M	Differential full scale	Bipolar mode, SD	16UNI = 0		-V _{REF} /2GAIN		+V _{REF} /2GAIN	
V _{ID,FSR}	input voltage range	Unipolar mode, SI	D16UNI = 1		0		+V _{REF} /2GAIN	mV
			SD16GAINx = 1			±500		
	Differential input		SD16GAINx = 2			±250		
	voltage range for		SD16GAINx = 4			±125		
V _{ID}	specified performance	SD16REFON=1	SD16GAINx = 8			±62		mV
	(see Note 1)		SD16GAINx = 16			±31		
			SD16GAINx = 32			±15		
		f _{SD16} = 1MHz,	SD16GAINx = 1			200		1.0
7	Input impedance	SD16BUFx = 00	SD16GAINx = 32	3 V		75		kΩ
ZI	(one input pin to AV _{SS})	f _{SD16} = 1MHz, SD16BUFx = 01	SD16GAINx = 1	3 V		>10		MΩ
		f _{SD16} = 1MHz,	SD16GAINx = 1		300	400		
7	Differential	SD16BUFx = 00	SD16GAINx = 32		100	150		kΩ
Z _{ID}	Input impedance (IN+ to IN-)	f _{SD16} = 1MHz, SD16BUFx > 00	SD16GAINx = 1	- 3V		>10		MΩ
	Absolute input	SD16BUFx = 00	·		AV _{SS} – 0.1V		AV _{CC}	
VI	voltage range	SD16BUFx > 00		1	AV _{SS}		AV _{CC} -1.2V	V
	Common-mode	SD16BUFx = 00			AV _{SS} – 0.1V		AV _{CC}	
V _{IC}	input voltage range	SD16BUFx > 00]	AV _{SS}		AV _{CC} -1.2V	V

NOTES: 1. The analog input range depends on the reference voltage applied to V_{REF}. If V_{REF} is sourced externally, the full-scale range is defined by V_{FSR+} = +(V_{REF}/2)/GAIN and V_{FSR-} = -(V_{REF}/2)/GAIN. The analog input range should not exceed 80% of V_{FSR+} or V_{FSR-}.



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

SD16_A, performance (f_{SD16} = 30kHz, SD16REFON = 1, SD16BUFx = 01)

P	ARAMETER	TEST CONDITIONS		V _{CC}	MIN	ТҮР	MAX	UNIT
		SD16GAINx = 1,Signal Amplitude = 500mV SD16OSRx = 256				84		
SINAD	Signal-to-noise + distortion ratio	SD16GAINx = 1,Signal Amplitude = 500mV SD16OSRx = 512	f _{IN} = 2.8Hz	3 V		84		dB
		SD16GAINx = 1,Signal Amplitude = 500mV SD16OSRx = 1024				84		
	Nominal gain	SD16GAINx = 1, SD16OSRx = 1024		3 V	0.97	1.00	1.02	
dG/dT	Gain temperature drift	SD16GAINx = 1, SD16OSRx = 1024 (see No	ote 1)	3 V		15		ppm/°C
dG/dV _{CC}	Gain supply voltage drift	SD16GAINx = 1, SD16OSRx = 1024, V _{CC} = (see Note 2)	2.5 V to 3.6 V			0.35		%/V

NOTES: 1. Calculated using the box method: (MAX(-40...85°C) - MIN(-40...85°C))/MIN(-40...85°C)/(85C - (-40°C))

2. Calculated using the box method: (MAX(2.5...3.6V) - MIN(2.5...3.6V))/MIN(2.5...3.6V)/(3.6V - 2.5V)

SD16_A, performance (f_{SD16} = 1MHz, SD16OSRx = 256, SD16REFON = 1, SD16BUFx = 00)

P	ARAMETER	TEST CONDITIONS		V _{CC}	MIN	ТҮР	МАХ	UNIT
		SD16GAINx = 1,Signal Amplitude = 500mV			83.5	85		
		SD16GAINx = 2,Signal Amplitude = 250mV			81.5	84		
	Signal-to-noise +	SD16GAINx = 4,Signal Amplitude = 125mV	f _{IN} = 50 Hz,	<u></u>	76	79.5		
SINAD	distortion ratio	SD16GAINx = 8,Signal Amplitude = 62mV	100 Hz	3 V	73	76.5		dB
		SD16GAINx = 16,Signal Amplitude = 31mV			69	73		
		SD16GAINx = 32,Signal Amplitude = 15mV			62	69		
		SD16GAINx = 1			0.97	1.00	1.02	
		SD16GAINx = 2			1.90	1.96	2.02	
•		SD16GAINx = 4			3.76	3.86	3.96	
G	Nominal gain	SD16GAINx = 8		3 V	7.36	7.62	7.84	
		SD16GAINx = 16			14.56	15.04	15.52	
		SD16GAINx = 32			27.20	28.35	29.76	
-	0."	SD16GAINx = 1		<u></u>			±0.2	
E _{OS}	Offset error	SD16GAINx = 32		3 V			±1.5	%FSR
	Offset error	SD16GAINx = 1		0.14		±4	±20	ppm
dE _{OS} /dT	temperature coefficient	SD16GAINx = 32		3 V		±20	±100	FSR/°C
01400	Common-mode	$ \begin{array}{l} SD16GAINx = 1, \mbox{ Common-mode input signal} \\ V_{ID} = 500 \mbox{ mV}, \mbox{ f}_{IN} = 50 \mbox{ Hz}, \mbox{ 100 Hz} \end{array} $:			>90		-
CMRR	rejection ratio	SD16GAINx = 32, Common-mode input signa V_{ID} = 16 mV, f _{IN} = 50 Hz, 100 Hz	al:	3 V		>75		dB
AC PSRR	AC power supply rejection ratio	SD16GAINx = 1, V _{CC} = 3 V \pm 100 mV, f _{VCC} =	= 50 Hz	3 V		>80		dB



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

SD16_A, temperature sensor

P/	ARAMETER	TEST CONDITIONS	v_{cc}	MIN	ТҮР	MAX	UNIT
TC _{Sensor}	Sensor temperature coefficient			1.18	1.32	1.46	mV/K
V _{Offset,sensor}	Sensor offset voltage			-100		100	mV
		Temperature sensor voltage at $T_A = 85^{\circ}C$		435	475	515	
V _{Sensor}	Sensor output voltage (see Note 2)	Temperature sensor voltage at $T_A = 25^{\circ}C$	3 V	355	395	435	mV
		Temperature sensor voltage at $T_A = 0^{\circ}C$		320	360	400	

NOTES: 1. The following formula can be used to calculate the temperature sensor output voltage:

V_{Sensor,typ} = TC_{Sensor} (273 + T [°C]) + V_{Offset,sensor} [mV]

2. Results based on characterization and/or production test, not TC_{Sensor} or $V_{Offset,sensor}$.

SD16_A, built-in voltage reference

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	ТҮР	MAX	UNIT
V _{REF}	Internal reference voltage	SD16REFON = 1, SD16VMIDON = 0	3 V	1.14	1.20	1.26	V
I _{REF}	Reference supply current	SD16REFON = 1, SD16VMIDON = 0	3 V		175	260	μA
TC	Temperature coefficient	SD16REFON = 1, SD16VMIDON = 0	3 V		18	50	ppm/K
C _{REF}	V _{REF} load capacitance	SD16REFON = 1, SD16VMIDON = 0 (see Note 1)			100		nF
I _{LOAD}	V _{REF(I)} maximum load current	SD16REFON = 1, SD16VMIDON = 0	3 V			±200	nA
t _{ON}	Turn-on time	SD16REFON = $0 \rightarrow 1$, SD16VMIDON = 0, C _{REF} = 100 nF	3 V		5		ms
DC PSR	DC power-supply rejection, $\Delta V_{REF} / \Delta V_{CC}$	SD16REFON = 1, SD16VMIDON = 0, V_{CC} = 2.5 V to 3.6 V			100		μV/V

NOTES: 1. There is no capacitance required on V_{REF}. However, a capacitance of at least 100nF is recommended to reduce any reference voltage noise.

SD16_A, reference output buffer

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{REF,BUF}	Reference buffer output voltage	SD16REFON = 1, SD16VMIDON = 1	3 V		1.2		V
I _{REF,BUF}	Reference supply + reference output buffer quiescent current	SD16REFON = 1, SD16VMIDON = 1	3 V		385	600	μA
C _{REF(O)}	Required load capacitance on V _{REF}	SD16REFON = 1, SD16VMIDON = 1		470			nF
I _{LOAD,Max}	Maximum load current on V _{REF}	SD16REFON = 1, SD16VMIDON = 1	3 V			±1	mA
	Maximum voltage variation vs load current	$ I_{LOAD} = 0$ to 1 mA	3 V	-15		+15	mV
t _{ON}	Turn-on time	SD16REFON = 0->1, SD16VMIDON = 1, $C_{REF} = 470 \text{ nF}$	3 V		100		μs

SD16_A, external reference input

	PARAMETER	TEST CONDITIONS	v_{cc}	MIN	ТҮР	MAX	UNIT
V _{REF(I)}	Input voltage range	SD16REFON = 0	3 V	1.0	1.25	1.5	V
I _{REF(I)}	Input current	SD16REFON = 0	3 V			50	nA



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

12-bit DAC, supply specifications

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	ТҮР	MAX	UNIT
AV _{CC}	Analog supply voltage	$AV_{CC} = DV_{CC},$ $AV_{SS} = DV_{SS} = 0 V$		2.20		3.60	V
I _{DD}	Supply current (see Notes 1 and 2)	DAC12AMPx = 2, DAC12IR=0, DAC12_xDAT=0800h			50	110	
		DAC12AMPx = 2, DAC12IR=1, DAC12_xDAT = 0800h, V _{REF,DAC12} = AV _{CC}			50	110	μΑ
		$\label{eq:DAC12AMPx} \begin{array}{l} DAC12AMPx = 5, DAC12IR = 1, \\ DAC12_xDAT = 0800h, V_{\mathsf{REF,DAC12}} = AV_{\mathsf{CC}} \end{array}$	2.2V/3V		200	440	
		DAC12AMPx=7, DAC12IR = 1, DAC12_xDAT = 0800h, $V_{REF,DAC12} = AV_{CC}$			700	1500	
PSRR	Power supply rejection ratio (see Notes 3 and 4)	DAC12_xDAT = 800h, $V_{REF,DAC12} = 1.2V$ $\Delta AV_{CC} = 100 \text{ mV}$	2.7V		70		dB

NOTES: 1. No load at the output pin assuming that the control bits for the shared pins are set properly.

2. Current into reference terminals not included. If DAC12IR = 1 current flows through the input divider; see Reference Input specifications.

PSRR = 20 × log{ΔAV_{CC}/ΔV_{DAC12_xOUT}}.
 V_{REF} is applied externally. The internal reference is not used.



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	ТҮР	MAX	UNIT
Resolution		12-bit monotonic		12			bits
INL	Integral nonlinearity (see Note 1)	V _{REF,DAC12} = 1.2 V, DAC12AMPx = 7, DAC12IR = 1	2.7 V		±2.0	±8.0	LSB
DNL	Differential nonlinearity (see Note 1)	V _{REF,DAC12} = 1.2 V, DAC12AMPx = 7, DAC12IR = 1	2.7 V		±0.4	±1.0	LSB
Eo	Offset voltage w/o calibration (see Notes 1, 2)	V _{REF,DAC12} = 1.2 V, DAC12AMPx = 7, DAC12IR = 1	2.7 V			±20	
	Offset voltage with calibration (see Notes 1, 2)	V _{REF,DAC12} = 1.2 V, DAC12AMPx = 7, DAC12IR = 1	2.7 V			±2.5	mV
d _{E(O)} /d _T	Offset error temperature coefficient (see Note 1)		2.7 V		±30		μV/C
E _G	Gain error (see Note 1)	V _{REF,DAC12} = 1.2 V	2.7 V			±3.50	% FSR
d _{E(G)} /d _T	Gain temperature coefficient (see Note 1)		2.7 V		10		ppm of FSR/°C
t _{Offset_Cal}	Time for offset calibration (see Note 3)	DAC12AMPx = 2	2.7 V			100	
		DAC12AMPx = 3, 5	2.7 V			32	ms
		DAC12AMPx = 4, 6, 7	2.7 V			6	

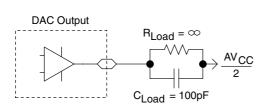
12-bit DAC, linearity specifications (see Figure 12)

NOTES: 1. Parameters calculated from the best-fit curve from 0x0A to 0xFFF. The best-fit curve method is used to deliver coefficients "a" and

"b" of the first order equation: $y = a + b^*x$. $V_{DAC12_xOUT} = E_O + (1 + E_G) * (V_{REF,DAC12}/4095) * DAC12_xDAT$, DAC12IR = 1.

2. The offset calibration works on the output operational amplifier. Offset calibration is triggered setting bit DAC12CALON.

3. The offset calibration can be done if DAC12AMPx = {2, 3, 4, 5, 6, 7}. The output operational amplifier is switched off with DAC12AMPx = {0, 1}. It is recommended that the DAC12 module be configured prior to initiating calibration. Port activity during calibration may effect accuracy and is not recommended.



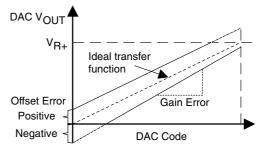


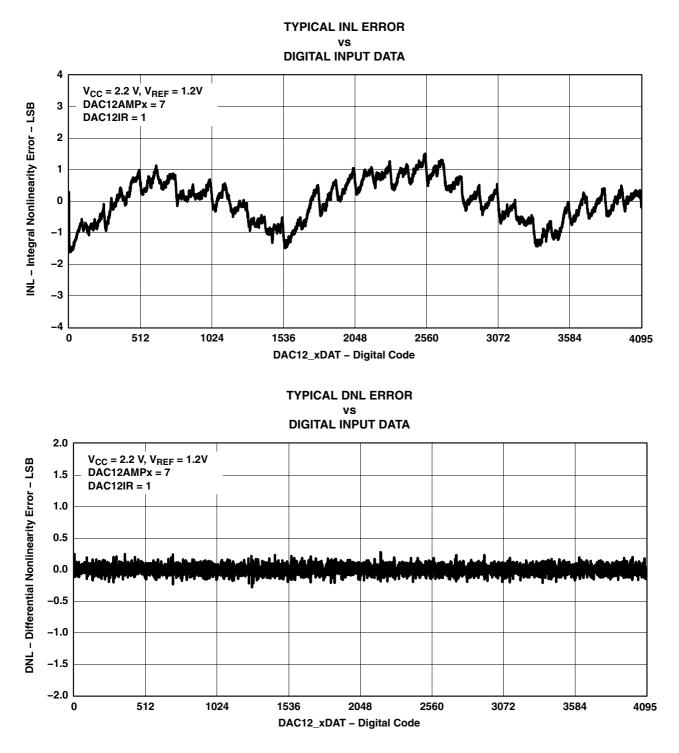
Figure 12. Linearity Test Load Conditions and Gain/Offset Definition



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

12-bit DAC, linearity specifications (continued)





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electrical characteristics over recommended operating free-air temperature (unless otherwise noted) (continued)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	ТҮР	МАХ	UNIT
	Output voltage range (see Note 1, Figure 15)	No load, $V_{REF,DAC12} = AV_{CC}$, DAC12_xDAT = 0h, DAC12IR = 1, DAC12AMPx = 7		0		0.005	
		No load, $V_{REF,DAC12} = AV_{CC}$, DAC12_xDAT = 0FFFh, DAC12IR = 1, DAC12AMPx = 7	0.01/01/	AV _{CC} -0.05		AV _{CC}	v
Vo		$eq:rescaled_$	- 2.2V/3V	0		0.1	
		$\label{eq:relation} \begin{split} R_{Load} &= 3 \ \text{k}\Omega, \ V_{REF,DAC12} = AV_{CC}, \\ DAC12_xDAT &= 0FFFh, \ DAC12IR = 1, \\ DAC12AMPx &= 7 \end{split}$		AV _{CC} -0.13		AV _{CC}	
C _{L(DAC12)}	Max DAC12 load capacitance		2.2V/3V			100	pF
	Max DAC12		2.2V	-0.5		+0.5	
I _{L(DAC12)}	load current		ЗV	-1.0		+1.0	mA
	Output ₂₎ resistance (see Figure 15)	$\label{eq:RLoad} \begin{split} &R_{Load} = 3 \; k\Omega, \; V_{O/P(DAC12)} < 0.3 \; V, \\ &DAC12AMPx = 2, \; DAC12_xDAT = 0h \end{split}$			150	250	
R _O /P(DAC12)		$eq:local_$	2.2V/3V		150	250	Ω
		$eq:local_$			1	4	

12-bit DAC, output specifications

NOTES: 1. Data is valid after the offset calibration of the output amplifier.

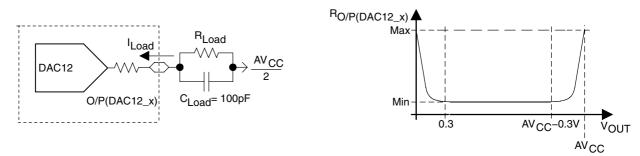


Figure 15. DAC12_x Output Resistance Tests



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted)

12-bit DAC, reference input specifications

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	ТҮР	MAX	UNIT
V _{REF}	Reference input	DAC12IR=0 (see Notes 1 and 2)	2.2V/3V		AV _{CC} /3	AV _{CC} +0.2	.,
	voltage range	DAC12IR=1 (see Notes 3 and 4)			AV _{CC}	AV _{CC} +0.2	V
Ri _(VREF)	Reference input	DAC12IR=0	0.01/01/	20			MΩ
	resistance	DAC12IR=1	2.2V/3V	40	48	56	kΩ

NOTES: 1. For a full-scale output, the reference input voltage can be as high as 1/3 of the maximum output voltage swing (AV_{CC}).

2. The maximum voltage applied at reference input voltage terminal $V_{REF} = [AV_{CC} - V_{E(O)}] / [3^{*}(1 + E_{G})]$.

3. For a full-scale output, the reference input voltage can be as high as the maximum output voltage swing (AV_{CC}).

4. The maximum voltage applied at reference input voltage terminal $V_{REF} = [AV_{CC} - V_{E(O)}] / (1 + E_G)$.

12-bit DAC, dynamic specifications, V_{REF.DAC12} = AV_{CC}, DAC12IR = 1 (see Figure 16 and Figure 17)

PARAMETER		TEST CONDITIONS		V _{cc}	MIN	TYP	MAX	UNIT
ton	D1 0/2	$\begin{array}{c} \text{DAC12_xDAT} = 800\text{h},\\ \text{Error}_{V(O)} < \pm 0.5 \text{ LSB}\\ (\text{see Note 1,Figure 16}) \end{array}$	$DAC12AMPx=0 \rightarrow \{2,3,4\}$			60	120	μs
	DAC12 on time		$DAC12AMPx=0 \rightarrow \{5,6\}$	2.2V/3V		15	30	
	on time		DAC12AMPx= $0 \rightarrow 7$			6	12	
-		e, DAC12_xDAT = $80h \rightarrow F7Fh \rightarrow 80h$	DAC12AMPx=2			100	200	μs
t _{S(FS)}	Settling time, full scale		DAC12AMPx=3,5	2.2V/3V		40	80	
TU	iuli scale		DAC12AMPx=4,6,7			15	30	
t _{S(C-C)}	Settling time, code to code	$13F8h \rightarrow 408h \rightarrow 3F8h$	DAC12AMPx=2			5		μs
			DAC12AMPx=3,5	2.2V/3V		2		
			DAC12AMPx=4,6,7			1		
		DAGIO DIT	DAC12AMPx=2		0.05	0.12		V/µs
SR	Slew rate	$\begin{array}{c} DAC12_xDAT = \\ 80h \rightarrow F7Fh \rightarrow 80h \end{array} \qquad \begin{array}{c} DAC12AMPx=3,5 \\ DAC12AMPx=4,6,7 \end{array} \qquad 2.2 V/DAC12AMPx=4,6,7 \end{array}$	DAC12AMPx=3,5	2.2V/3V	0.35	0.7		
				1.5	2.7			
			DAC12AMPx=2			10		
Glitch energy, full scale		DAC12_xDAT =	DAC12AMPx=3,5	2.2V/3V		10		nV-s
		80h→ F7Fh→ 80h	DAC12AMPx=4,6,7			15		1

NOTES: 1. R_{Load} and C_{Load} connected to AV_{SS} (not $AV_{CC}/2$) in Figure 16.

2. Slew rate applies to output voltage steps \geq 200mV.

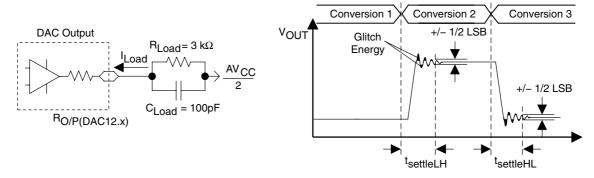


Figure 16. Settling Time and Glitch Energy Testing



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted)

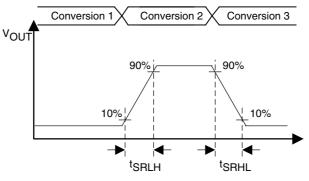


Figure 17. Slew Rate Testing

	PARAMETER	TEST CONDITIONS	Vcc	MIN	ТҮР	MAX	UNIT
		DAC12AMPx = {2, 3, 4}, DAC12SREFx = 2, DAC12IR = 1, DAC12_xDAT = 800h		40			
BW _{-3dB}	3-dB bandwidth, V _{DC} =1.5 V, V _{AC} =0.1 V _{PP}	DAC12AMPx = {5, 6}, DAC12SREFx = 2, DAC12IR = 1, DAC12_xDAT = 800h	2.2V/3V	180			kHz
	(see Figure 18)	DAC12AMPx = 7, DAC12SREFx = 2, DAC12IR = 1, DAC12_xDAT = 800h		550			

NOTES: 1. $R_{LOAD} = 3 \text{ k}\Omega$, $C_{LOAD} = 100 \text{ pF}$

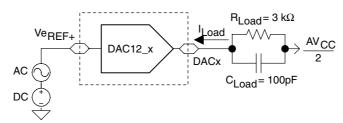


Figure 18. Test Conditions for 3-dB Bandwidth Specification



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted)

operational amplifier OA, supply specifications

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	ТҮР	MAX	UNIT
V _{CC}	Supply voltage		—	2.2		3.6	V
		Fast Mode			180	290	
ICC	Supply current (see Note 1)	Medium Mode	2.2 V/3 V		110	190	μA
		Slow Mode			50	80	
PSRR	Power supply rejection ratio	Non-inverting	2.2 V/3 V		70		dB

NOTES: 1. P6SEL.x = 1 or SD16AE.x = 1 for each corresponding pin when used in OA input or OA output mode.

operational amplifier OA, input/output specifications

	PARAMETER	TEST CON	DITIONS	V _{CC}	MIN	ТҮР	МАХ	UNIT	
V _{I/P}	Input voltage, I/P			—	-0.1		V _{CC} -1.2	V	
	Input leakage current, I/P	$T_A = -40^{\circ}C$ to $55^{\circ}C$			-5	±0.5	5	nA	
l _{lkg}	(see Notes 1 and 2)	$T_A = 55^{\circ}C$ to $85^{\circ}C$		—	-20	±5	20	nA	
		Fast Mode				50			
		Medium Mode	f _{V(I/P)} = 1 kHz			80		nA nA nV/√Hz mV/√Hz mV/℃ mV/∨ V	
	Matterna and a structure I/D	Slow Mode				140			
V _n v	Voltage noise density, I/P	Fast Mode				30			
		Medium Mode	f _{V(I/P)} = 10 kHz			50			
		Slow Mode				65			
V _{IO}	Offset voltage, I/P			2.2 V/3 V			±10	mV	
	Offset temperature drift, I/P	see Note 3		2.2 V/3 V		±10		μV/°C	
	Offset voltage drift with supply, I/P	$\begin{array}{l} 0.3V \leq V_{IN} \leq V_{CC} 0.3\\ \Delta V_{CC} \leq \pm \ 10\%, \ T_A = 2 \end{array}$		2.2 V/3 V			±1.5	mV/V	
	Litely local systematic allocation O/D	Fast Mode, I _{SOURCE}	≤ –500 μA	2.2 V	V _{CC} -0.2		V _{CC}		
V _{OH} High-level output voltage, O/F		Slow Mode, I _{SOURCE}	≤ –150 μA	3 V	V _{CC} -0.1		V _{CC}	V	
		Fast Mode, I _{SOURCE}	≤ +500 μA	2.2 V	V _{SS}		0.2		
V _{OL}	Low-level output voltage, O/P	Slow Mode, ISOURCE	≤ +150 μA	3 V	V _{SS}		0.1	V	
CMRR	Common-mode rejection ratio	Non-inverting		2.2 V/3 V		70		dB	

NOTES: 1. ESD damage can degrade input current leakage.

2. The input bias current is overridden by the input leakage current.

3. Characterized and calculated using the box method, not production tested.

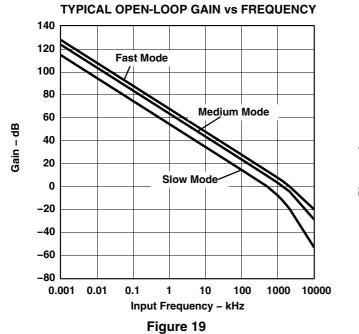


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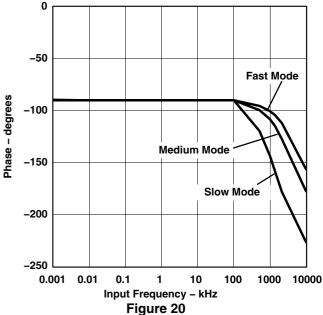
electrical characteristics over recommended operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	ТҮР	МАХ	UNIT
		Fast Mode			1.2		
SR	Slew rate	Medium Mode	_		0.8		V/µs
		Slow Mode			0.3		
	Open-loop voltage gain		—		100		dB
φ _m	Phase margin	C _L = 50 pF	_		60		deg
	Gain margin	C _L = 50 pF	_		20		dB
	Gain-bandwidth product	Noninverting, Fast Mode, $R_L = 47k\Omega$, $C_L = 50pF$			2.2		
GBW	(see Figure 19	Noninverting, Medium Mode, $R_L = 300 k\Omega$, $C_L = 50 pF$	2.2 V/3 V		1.4		MHz
	and Figure 20)	Noninverting, Slow Mode, $R_L = 300 k\Omega$, $C_L = 50 pF$			0.5		
t _{en(on)}	Enable time on	t _{on} , noninverting, Gain = 1	2.2 V/3 V		10	20	μs
t _{en(off)}	Enable time off		2.2 V/3 V			1	μs

operational amplifier OA, dynamic specifications







switches to ground

	PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	МАХ	UNIT
V _{CC}	Supply voltage			2.5		3.6	V
	Input leakage current	$T_A = -40^{\circ}C \text{ to } + 55^{\circ}C$			±1	±10	
I _{lkg} (see Note 1)	$T_A = 55^{\circ}C$ to $85^{\circ}C$				±50	nA	
I _{IN}	Input current	Input switched to Ground.		0		100	μA
R _{ON}	On resistance	I _{IN} =100 μA, T _A =-40°C to 85°C				10	Ω
NOTES:	 ESD damage can degr 	ade input current leakage.	•				



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electrical characteristics over recommended operating free-air temperature (unless otherwise noted)

flash memory

	PARAMETER	TEST CONDITIONS	v _{cc}	MIN	ТҮР	МАХ	UNIT
V _{CC(PGM/} ERASE)	Program and erase supply voltage			2.5		3.6	V
f _{FTG}	Flash timing generator frequency			257		476	kHz
I _{PGM}	Supply current from DV _{CC} during program		2.5V/3.6V		3	5	mA
I _{ERASE}	Supply current from DV _{CC} during erase		2.5V/3.6V		3	7	mA
t _{CPT}	Cumulative program time	see Note 1	2.5V/3.6V			10	ms
t _{CMErase}	Cumulative mass erase time	see Note 2	2.5V/3.6V	200			ms
	Program/erase endurance			10 ⁴	10 ⁵		cycles
t _{Retention}	Data retention duration	$T_J = 25^{\circ}C$		100			years
t _{Word}	Word or byte program time				35		
t _{Block, 0}	Block program time for 1 st byte or word				30		
t _{Block, 1-63}	Block program time for each additional byte or word	1			21		
t _{Block} , End	Block program end-sequence wait time	see Note 3			6		t _{FTG}
t _{Mass Erase}	Mass erase time	1			5297		
t _{Seg Erase}	Segment erase time	1			4819		

NOTES: 1. The cumulative program time must not be exceeded when writing to a 64-byte flash block. This parameter applies to all programming methods: individual word/byte write and block write modes.

2. The mass erase duration generated by the flash timing generator is at least 11.1ms (= 5297x1/f_{FTG},max = 5297x1/476kHz). To achieve the required cumulative mass erase time the Flash Controller's mass erase operation can be repeated until this time is met. (A worst case minimum of 19 cycles are required).

3. These values are hardwired into the Flash Controller's state machine (t_{FTG} = 1/f_{FTG}).

JTAG interface

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	ТҮР	МАХ	UNIT
4		ana Nata 1	2.2 V	0		5	MHz
[†] TCK	TCK input frequency	see Note 1	3 V	0		10	MHz
R _{Internal}	Internal pull-up resistance on TMS, TCK, TDI/TCLK	see Note 2	2.2 V/ 3 V	25	60	90	kΩ

NOTES: 1. f_{TCK} may be restricted to meet the timing requirements of the module selected.

2. TMS, TDI/TCLK, and TCK pull-up resistors are implemented in all versions.

JTAG fuse (see Note 1)

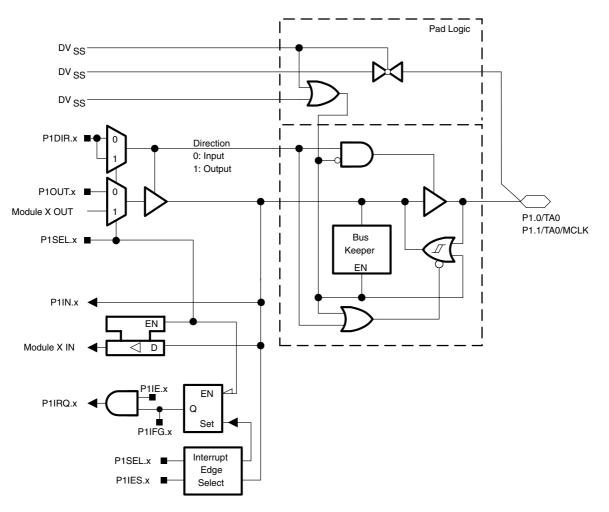
	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	ТҮР	МАХ	UNIT
V _{CC(FB)}	Supply voltage during fuse-blow condition	$T_A = 25^{\circ}C$		2.5			V
V_{FB}	Voltage level on TDI/TCLK for fuse-blow: F versions			6		7	V
I _{FB}	Supply current into TDI/TCLK during fuse blow					100	mA
t _{FB}	Time to blow fuse					1	ms

NOTES: 1. Once the fuse is blown, no further access to the MSP430 JTAG/Test and emulation features is possible. The JTAG block is switched to bypass mode.



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input/output schematics



Port P1 pin schematic: P1.0, P1.1, input/output with Schmitt trigger

Note: x = 0,1

Port P1 (P1.0, P1.1) pin functions

PIN NAME (P1.X)	v	FUNCTION	CONTROL BITS / SIGNALS			
	X	FUNCTION	P1DIR.x	P1SEL.x		
P1.0/TA0		P1.0† Input/Output	0/1	0		
		Timer_A3.CCI0A	0	1		
		Timer_A3.TA0	1	1		
P1.1/TA0/MCLK	1	P1.1† Input/Output	0/1	0		
		Timer_A3.CCI0B	0	1		
		MCLK	1	1		

[†] Default after reset (PUC/POR)

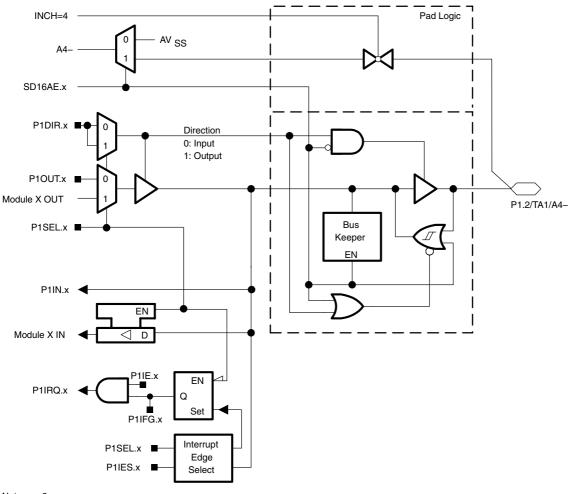
NOTES: 1. N/A: Not available or not applicable.

2. X: Don't care.



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Port P1 pin schematic: P1.2, input/output with Schmitt trigger and analog functions



Note: x = 2

Port P1 (P1.2) pin functions

PIN NAME (P1.X)	v	FUNCTION	CONTROL BITS / SIGNALS					
	X		P1DIR.x	P1SEL.x	SD16AE.x			
P1.2/TA1/A4-	2	P1.2† Input/Output	0/1	0	0			
		Timer_A3.CCI1A	0	1	0			
		Timer_A3.TA1	1	1	0			
		A4- (see Notes 3, 4)	Х	Х	1			

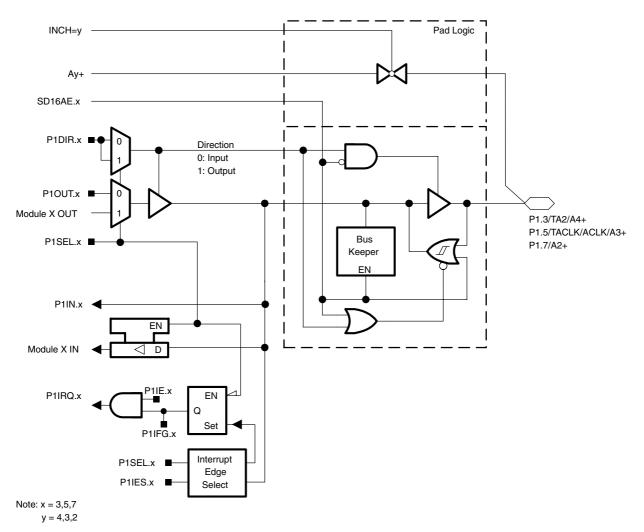
[†] Default after reset (PUC/POR)

NOTES: 1. N/A: Not available or not applicable.

- 2. X: Don't care.
- 3. Setting the SD16AE.x bit disables the output driver as well as the input Schmitt trigger to prevent parasitic cross currents when applying analog signals.
- 4. Negative input to SD16_A (A4-) connected to V_{SS} if corresponding SD16AE.x bit is cleared.



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Port P1 pin schematic: P1.3, P1.5, P1.7, input/output with Schmitt trigger and analog functions



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Port P1 (P1.3, P1.5, P1.7) pin functions

	~		CONT	ROL BITS / SIG	NALS
PIN NAME (P1.X)	X	FUNCTION	P1DIR.x	P1SEL.x	SD16AE.x
P1.3/TA2/A4+	3	P1.3† Input/Output	0/1	0	0
		Timer_A3.CCI2A	0	1	0
		Timer_A3.TA2	1	1	0
		A4+ (see Note 3)	Х	Х	1
P1.5/TACLK/ACLK/A3+	5	P1.5† Input/Output	0/1	0	0
		Timer_A3.TACLK/INCLK	0	1	0
		ACLK	1	1	0
		A3+ (see Note 3)	Х	Х	1
P1.7/A2+	7	P1.5† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		A2+ (see Note 3)	Х	Х	1

[†] Default after reset (PUC/POR)

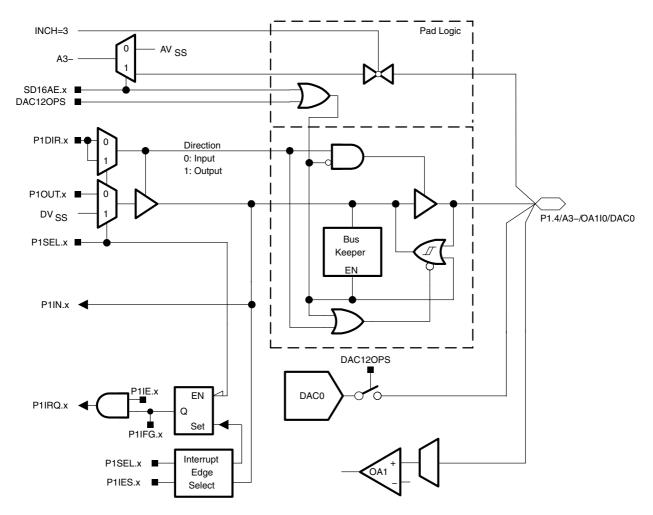
NOTES: 1. N/A: Not available or not applicable.

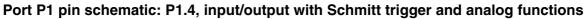
2. X: Don't care.

3. Setting the SD16AE.x bit disables the output driver as well as the input Schmitt trigger to prevent parasitic cross currents when applying analog signals.



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Note: x = 4

Port P1 (P1.4) pin functions

PIN NAME (P1.X)	v	FUNCTION	CONTROL BITS / SIGNALS						
	х	FUNCTION	P1DIR.x	P1SEL.x	SD16AE.x	OAPx (OA1)	DAC12OPS		
P1.4/A3-/OA1I0/DAC0	4	P1.4† Input/Output	0/1	0	0	XX	0		
				N/A	0	1	0	XX	0
					DVSS	1	1	0	XX
		A3- (see Notes 3, 4)	х	Х	1	XX	0		
		OA1I0	х	Х	1	00	0		
		DAC0 (see Note 5)	Х	Х	Х	XX	1		

[†] Default after reset (PUC/POR)

NOTES: 1. N/A: Not available or not applicable.

2. X: Don't care.

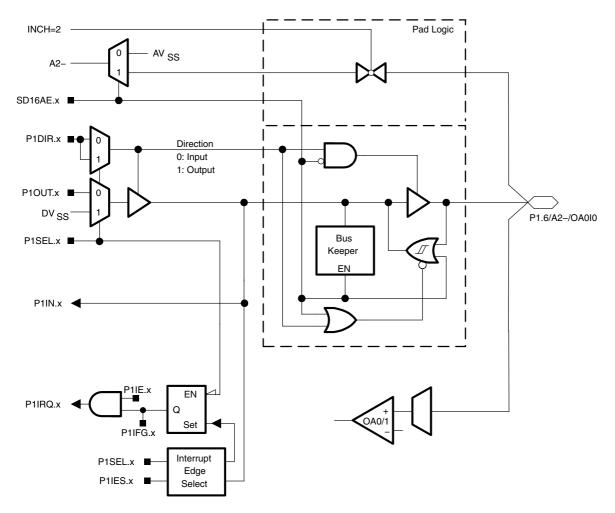
3. Setting the SD16AE.x bit disables the output driver as well as the input Schmitt trigger to prevent parasitic cross currents when applying analog signals.

- 4. Negative input to SD16_A (A3-) connected to AV_{SS} if corresponding SD16AE.x bit is cleared.
- 5. Setting the DAC12OPS bit also disables the output driver as well as the input Schmitt trigger to prevent parasitic cross currents when applying analog signals.



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Port P1 pin schematic: P1.6, input/output with Schmitt trigger and analog functions



Note: x = 6

Port P1 (P1.6) pin functions

	v	FUNCTION	CONTROL BITS / SIGNALS						
PIN NAME (P1.X)	x	FUNCTION	P1DIR.x	P1SEL.x	SD16AE.x	OAPx (OA0)	OAPx (OA1)		
P1.6/A2-/OA0I0 6		P1.6† Input/Output	0/1	0	0	XX	XX		
		N/A	0	1	0	XX	XX		
		DVSS	1	1	0	XX	XX		
		A2- (see Notes 3, 4)	Х	Х	1	XX	XX		
			Х	Х	1	00 or 01	XX		
		OA0I0 (see Note 5)	Х	Х	1	XX	01		

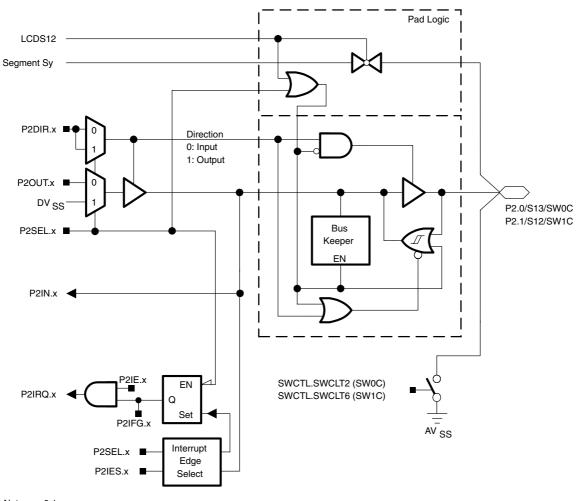
[†] Default after reset (PUC/POR)

NOTES: 1. N/A: Not available or not applicable.

- 2. X: Don't care.
- 3. Setting the SD16AE.x bit disables the output driver as well as the input Schmitt trigger to prevent parasitic cross currents when applying analog signals.
- 4. Negative input to SD16_A (A2-) connected to AV_{SS} if corresponding SD16AE.x bit is cleared.
- 5. OA0I0 connected to pin if for OA0 the OAPx bits are cleared or set to 01, or if for OA1 the OAPx bits are set to 01.



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Port P2 pin schematic: P2.0 to P2.1, input/output with Schmitt trigger, LCD and analog functions

Note: x = 0,1 y = 13,12

Port P2 (P2.0, P2.1) pin functions

	v	FUNCTION	CONTROL BITS / SIGNALS			
PIN NAME (P2.X)	X	FUNCTION	P2DIR.x	P2SEL.x	LCDS12	
P2.0/S13/SW0C	0	P2.0† Input/Output	0/1	0	0	
		SW0C (see Notes 3, 4)	Х	1	0	
		S13	Х	Х	1	
P2.1/S12/SW1C	1	P2.1† Input/Output	0/1	0	0	
		SW1C (see Notes 3, 4)	Х	1	0	
		S12	х	Х	1	

[†] Default after reset (PUC/POR)

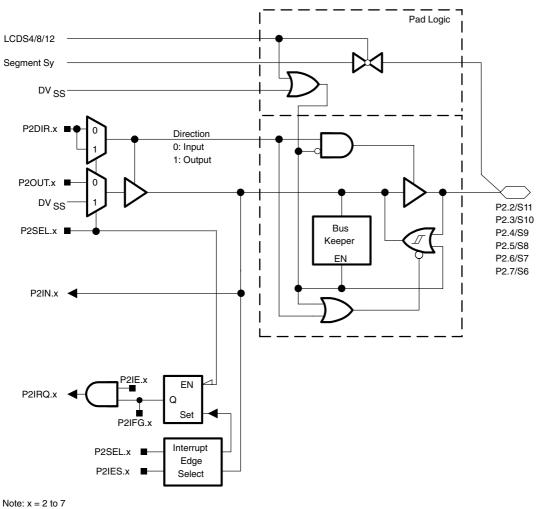
NOTES: 1. N/A: Not available or not applicable.

- 2. X: Don't care.
- 3. Setting the P2SEL.x bit disables the output driver as well as the input Schmitt trigger to prevent parasitic cross currents when applying analog signals.
- 4. The low impedance switch to ground is closed by setting the corresponding bits in SWCTL register.



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Port P2 pin schematic: P2.2 to P2.7, input/output with Schmitt trigger, LCD and analog functions



y = 11 to 6



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	.	FUNCTION	CONT	ROL BITS / SIG	NALS
PIN NAME (P2.X)	x	FUNCTION	P2DIR.x	P2SEL.x	LCDS12
P2.2/S11	2	P2.2† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S11	Х	Х	1
P2.3/S10	3	P2.3† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S10	Х	Х	1
P2.4/S9	4	P2.4† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S9	Х	1 1 X X	1
P2.5/S8	5	P2.5† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S8	Х	Х	1
P2.6/S7	6	P2.6† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S7	Х	Х	1
P2.7/S6	7	P2.7† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S6	Х	Х	1

Port P2 (P2.0 to P2.7) pin functions

[†] Default after reset (PUC/POR)

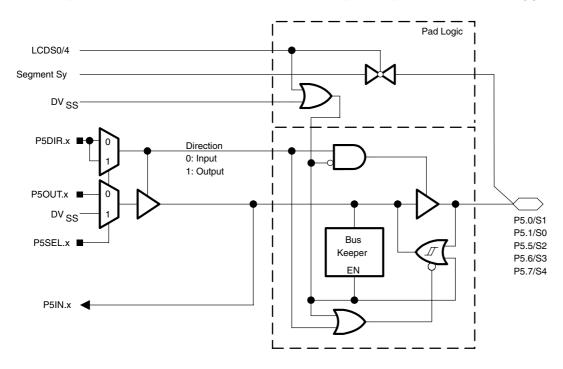
NOTES: 1. N/A: Not available or not applicable.

2. X: Don't care.



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Port P5 pin schematic: P5.0, P5.1, P5.5 to P5.7, input/output with Schmitt trigger and LCD functions



Note: x = 0,1,5,6,7 y = 1,0,2,3,4



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	~		CONT	ROL BITS / SIG	NALS
PIN NAME (P5.X)	X	FUNCTION	P5DIR.x	P5SEL.x	LCDS0
P5.0/S1	0	P5.0† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S1	Х	Х	1
P5.1/S0	1	P5.1† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S0	Х	Х	1
P5.5/S2	5	P5.5† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S2	Х	Х	1
P5.6/S3	6	P5.6† Input/Output	0/1	0	0
		N/A	0	1	0
		DVSS	1	1	0
		S3	Х	Х	1

Port P5 (P5.0, P5.1, P5.5, P5.6) pin functions

[†] Default after reset (PUC/POR)

NOTES: 1. N/A: Not available or not applicable.

2. X: Don't care.

Port P5 (P5.7) pin functions

PIN NAME (P5.X)	×	FUNCTION	CONTROL BITS / SIGNALS			
FIN NAME (F5.A)	х	FUNCTION	P5DIR.x	P5SEL.x	LCDS4	
P5.7/S4	7	P5.7† Input/Output	0/1	0	0	
		N/A	0	1	0	
		DVSS	1	1	0	
		S4	Х	Х	1	

[†] Default after reset (PUC/POR)

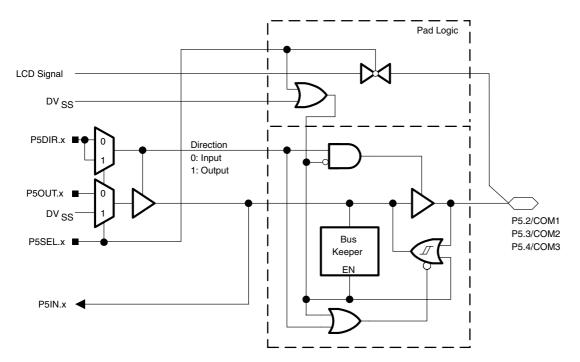
NOTES: 1. N/A: Not available or not applicable.

2. X: Don't care.



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Port P5 pin schematic: P5.2 to P5.4, input/output with Schmitt trigger and LCD functions



Note: x = 2 to 4

Port P5 (P5.2 to P5.4) pin functions

	x	50005000	CONTROL BITS / SIGNALS		
PIN NAME (P5.X)		FUNCTION	P5DIR.x	P5SEL.x	
P5.2/COM1	2	P5.2† Input/Output	0/1	0	
		COM1	Х	1	
P5.3/COM2	3	P5.3† Input/Output	0/1	0	
		COM2	Х	1	
P5.4/COM3	4	P5.4† Input/Output	0/1	0	
		COM3	Х	1	

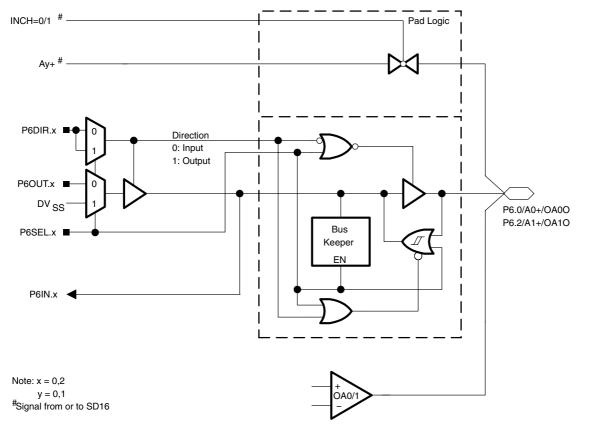
[†] Default after reset (PUC/POR)

NOTES: 1. N/A: Not available or not applicable.

2. X: Don't care.



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Port P6 pin schematic: P6.0, P6.2, input/output with Schmitt trigger and analog functions

Port P6 (P6.0, P6.2) pin functions

PIN NAME (P6.X)	x	FUNCTION	CONTROL BITS / SIGNALS		
FIN NAME (FO.A)		FUNCTION	P6DIR.x	P6SEL.x	
P6.0/A0+/OA0O	0	P6.0† Input/Output	0/1	0	
		A0+/OA0O (see Note 3)	Х	1	
P6.2/A1+/OA1O	2	P6.2† Input/Output	0/1	0	
		A1+/OA1O (see Note 3)	Х	1	

[†] Default after reset (PUC/POR)

NOTES: 1. N/A: Not available or not applicable.

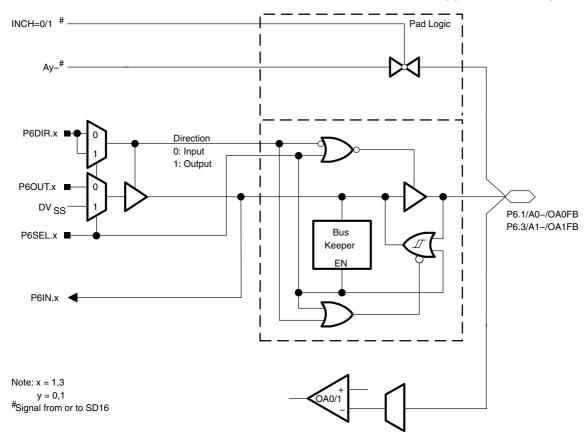
2. X: Don't care.

3. Setting the P6SEL.x bit disables the output driver as well as the input Schmitt trigger to prevent parasitic cross currents when applying analog signals.



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Port P6 pin schematic: P6.1, P6.3, input/output with Schmitt trigger and analog functions



Port P6 (P6.1, P6.3) pin functions

	x	FUNCTION	CONTROL BITS / SIGNALS		
PIN NAME (P6.X)		FUNCTION	P6DIR.x	P6SEL.x	
P6.1/A0-/OA0FB	1	P6.1† Input/Output	0/1	0	
		A0-/OA0FB (see Note 3)	Х	1	
P6.3/A1–/OA1FB	3	P6.3† Input/Output	0/1	0	
		A1–/OA1FB (see Note 3)	Х	1	

[†] Default after reset (PUC/POR)

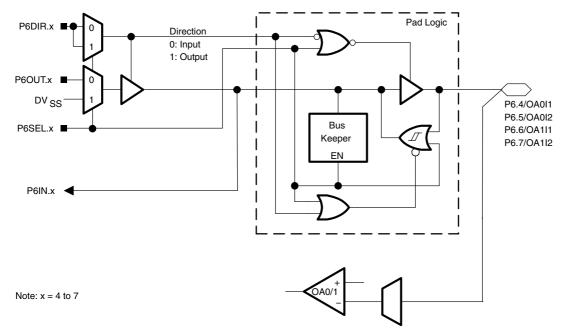
NOTES: 1. N/A: Not available or not applicable.

2. X: Don't care.

3. Setting the P6SEL.x bit disables the output driver as well as the input Schmitt trigger to prevent parasitic cross currents when applying analog signals.



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Port P6 pin schematic: P6.4 to P6.7, input/output with Schmitt trigger and analog functions

Port P6 (P6.4 to P6.7) pin functions

PIN NAME (P6.X)	v	FUNCTION	CONTROL BITS / SIGNALS		
	X	FUNCTION	P6DIR.x	P6SEL.x	
P6.4/OA0I1	4	P6.4† Input/Output	0/1	0	
		OA0I1 (see Note 3)	Х	1	
P6.5/OA0I2	5	P6.5† Input/Output	0/1	0	
		OA0I2 (see Note 3)	Х	1	
P6.6/OA1I1	6	P6.6† Input/Output	0/1	0	
		OA1I1 (see Note 3)	Х	1	
P6.7/OA1I2	7	P6.7† Input/Output	0/1	0	
		OA1I2 (see Note 3)	Х	1	

[†] Default after reset (PUC/POR)

NOTES: 1. N/A: Not available or not applicable.

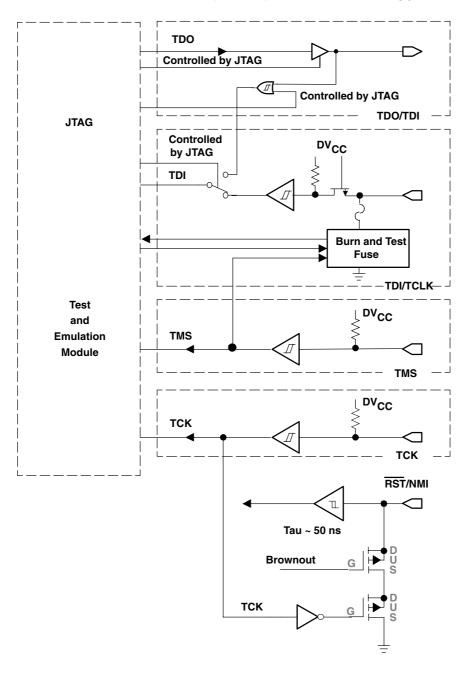
2. X: Don't care.

3. Setting the P6SEL.x bit disables the output driver as well as the input Schmitt trigger to prevent parasitic cross currents when applying analog signals.



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JTAG pins TMS, TCK, TDI/TCLK, TDO/TDI, input/output with Schmitt trigger or output





JTAG fuse check mode

MSP430 devices that have the fuse on the TDI/TCLK terminal have a fuse check mode that tests the continuity of the fuse the first time the JTAG port is accessed after a power-on reset (POR). When activated, a fuse check current ($I_{(TF)}$) of 1 mA at 3 V can flow from the TDI/TCLK pin to ground if the fuse is not burned. Care must be taken to avoid accidentally activating the fuse check mode and increasing overall system power consumption.

Activation of the fuse check mode occurs with the first negative edge on the TMS pin after power up or if the TMS is being held low during power up. The second positive edge on the TMS pin deactivates the fuse check mode. After deactivation, the fuse check mode remains inactive until another POR occurs. After each POR the fuse check mode has the potential to be activated.

The fuse check current only flows when the fuse check mode is active and the TMS pin is in a low state (see Figure 21). Therefore, the additional current flow can be prevented by holding the TMS pin high (default condition). The JTAG pins are terminated internally and therefore do not require external termination.

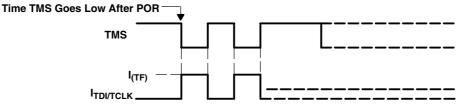


Figure 21. Fuse Check Mode Current



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Data Sheet Revision History

Literature Number	Summary
SLAS556	Product Preview data sheet release
SLAS556A	Production Data data sheet release

NOTE: Page and figure numbers refer to the respective document revision.



PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
MSP430FG4250IDL	ACTIVE	SSOP	DL	48	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430FG4250IDLR	ACTIVE	SSOP	DL	48	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430FG4250IRGZR	ACTIVE	QFN	RGZ	48	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430FG4250IRGZT	ACTIVE	QFN	RGZ	48	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430FG4260IDL	ACTIVE	SSOP	DL	48	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430FG4260IDLR	ACTIVE	SSOP	DL	48	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430FG4260IRGZR	ACTIVE	QFN	RGZ	48	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430FG4260IRGZT	ACTIVE	QFN	RGZ	48	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430FG4270IDL	ACTIVE	SSOP	DL	48	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430FG4270IDLR	ACTIVE	SSOP	DL	48	1000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430FG4270IRGZR	ACTIVE	QFN	RGZ	48	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR
MSP430FG4270IRGZT	ACTIVE	QFN	RGZ	48	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details. **TBD:** The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

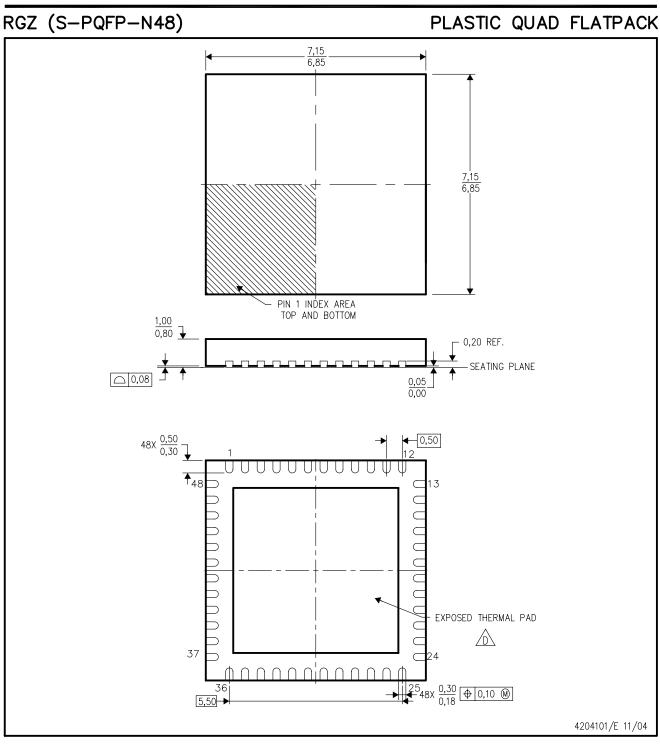
⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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MECHANICAL DATA



NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Quad Flatpack, No-leads (QFN) package configuration.

The package thermal pad must be soldered to the board for thermal and mechanical performance. See the Product Data Sheet for details regarding the exposed thermal pad dimensions.

E. Falls within JEDEC MO-220.



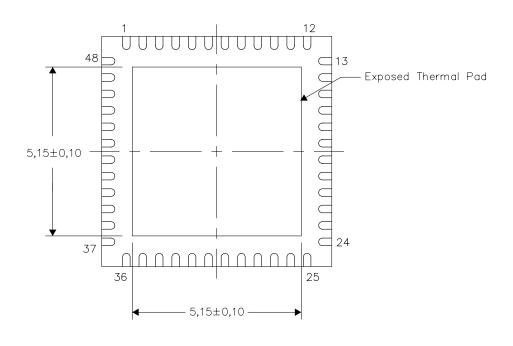


THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, Quad Flatpack No-Lead Logic Packages, Texas Instruments Literature No. SCBA017. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

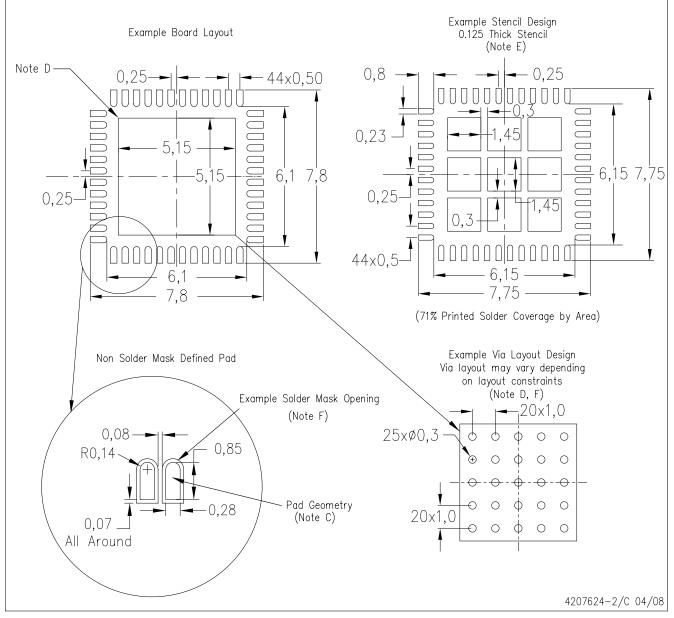




NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions

RGZ (S-PVQFN-N48)



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SCBA017, SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.



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